



PRELIMINARY
September 2003
Revision 1.0

PC87427 Server I/O with SensorPath™ Health Monitoring

General Description

The National Semiconductor PC87427 is targeted for a wide range of servers, workstations and high-end desktops that use the Low Pin Count (LPC) bus for the host interface and an SMBus® interface for either a Baseboard Management Controller (BMC) or mini-BMC (mBMC), both of which are optional.

For LPC and SMBus access, the PC87427 features a fast X-Bus, over which boot flash and I/O devices can be accessed. The PC87427 supports X-Bus address line forcing (to 0 or 1) to create memory windows for BIOS data storage.

When V_{SB} exists, the BMC or mBMC can access the PC87427 and its fast X-Bus via SMBus. The SMBus also controls serial port float, RTC access, and serial port interconnection (snoop and take-over modes). In addition, the PC87427 provides routing of up to two selected LPC I/O port transactions to the GPIO Extension Port.

The PC87427 provides a V_{SB} -powered high-frequency clock for on-chip peripherals; it also provides a configurable high-frequency clock for other V_{SB} -powered platform components.

The PC87427 supports SensorPath health monitor interface to LMPCxx sensors, fan monitoring and control, and a chassis intrusion detector.

The System Wake-Up Control (SWC) module supports flexible wake-up and power-off request mechanisms for all platforms (i.e., with or without BMC/mBMC).

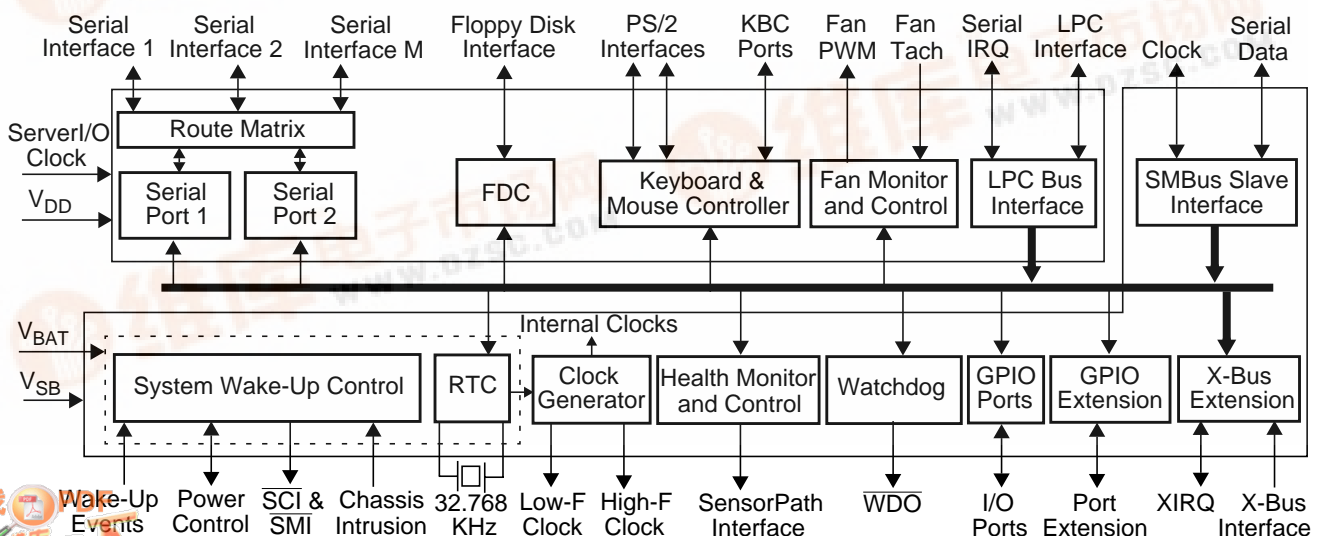
The PC87427 supports both I/O and memory mapping of module registers and enables building legacy-free systems.

The PC87427 also incorporates a Floppy Disk Controller (FDC), two serial ports (UARTs), a Keyboard and Mouse Controller (KBC), General-Purpose Input/Output (GPIO), GPIO extension for additional off-chip GPIO ports, and an interrupt serializer for parallel IRQs.

Outstanding Features

- Legacy-reduced Advanced I/O, optimized for high-end platforms. Legacy modules: FDC, two Serial Ports (UARTs) and a Keyboard and Mouse Controller (KBC).
- SensorPath system health support for LMXX sensors, fan monitor/control, and chassis intrusion detection, for all platforms (i.e., with or without a BMC or mBMC).
- 8/16-bit fast X-Bus extension for boot flash, memory and I/O.
- I/O-mapped and memory-mapped registers.
- V_{SB} -powered SMBus access to modules and fast X-Bus.
- Two sets of BIOS code and data support, for main and back-up BIOS.
- Extremely low current consumption in Battery Backup mode.
- Serial Interface for manageability (Serial Interface M). Two-to-one multiplexing of Serial Ports 1 and 2.
- 52 GPIO ports with a variety of wake-up events, plus GPIO extension for additional off-chip GPIO ports.
- Watchdog for autonomous system recovery for BIOS Boot process and for operating system use.
- 128-pin PQFP package.

Block Diagram



Features

System Health Support

- SensorPath interface to sensors optimizes digital/analog partitioning
 - Simplifies board design and routing
 - Supports distributed sensors and centralized control
 - Off-loads SMBus, faster boot time
- Fan Monitor and Control (FMC)
 - Four PWM-based fan controls
 - Eight 16-bit resolution tachometer inputs
 - Software or local temperature feedback control
- Chassis intrusion detection

Bus Interfaces

- LPC Bus Interface
 - Based on Intel's *LPC Interface Specification Revision 1.0, September 29, 1997*
 - Synchronous cycles using up to 33 MHz bus clock
 - 8-bit I/O and 8-bit Memory read and write cycles
 - Up to four 8-bit DMA channels
 - Serial IRQ
 - Supports bootable memory
 - Supports LPC and FWH boot transactions
 - Supports registers memory and I/O mapping
- SMBus Interface
 - Compliant with *SMBus Specification Revision 2.0, August 3, 2000*
 - Enables a system controller to access the internal functions and the fast X-Bus extension
 - Proprietary commands for read/write byte from/to:
 - Internal register
 - X-Bus I/O device
 - X-Bus memory device
 - Slave address:
 - One of two values selected by strap
 - Programmable through the LPC bus
 - V_{BAT} backed-up
 - Supports $SMBALERT$
 - Concurrent access with the LPC bus
 - V_{SB} powered
 - Optional internal pull-up on the two SMBus pins
- Fast X-Bus Extension
 - Supports I/O and memory read/write operations
 - 8- or 16-bit data bus, 28-bit addressing
 - Accessible from both LPC bus and SMBus
 - V_{SB} powered
 - Boot configuration selected by straps
 - Programmable protection control for access from the LPC bus
 - Supports three XIRQ external interrupts

- Multiplexed address-data lines:
 - Four direct address lines
 - Partial non-multiplexed option
- Four chip-select outputs, each supporting multiple zones:
 - Two BIOS memory zones (up to 32 Mbytes total)
 - Two user-defined memory zones (up to 32 Mbytes total)
 - Four user-defined I/O zones
- Address line forcing (to 0 or 1) for access to two BIOS code and data sets
- Optional indirect addressing of memory
- \overline{XRD} -XEN or \overline{XWR} -XR/W mode support
- Supports both slow and fast devices
- For faster transactions in 16-bit data bus, strobe signals for address latches change automatically only when the address is changed
- Configuration Control
 - Compliant with *PC01 Specification Revision 1.0, 1999-2000*
 - Compliant with *Hardware Design Guide Version 3.0 for Microsoft Windows 2000 Server, June 30 2000*
 - Plug and Play (PnP) Configuration register structure
 - Base Address strap, to setup the address of the Index-Data register pair
 - Flexible resource allocation for all logical devices:
 - Relocatable base address
 - 15 IRQ routing options to serial IRQ
 - Up to four optional 8-bit DMA channels
 - SMBus control over pin multiplexing, module disable and output TRI-STATE[®] for all Legacy modules

Legacy Modules

- Serial Ports 1 and 2
 - Software compatible with the 16550A and the 16450
 - Supports shadow register for write-only bit monitoring
 - UART data rates up to 1.5 Mbaud
 - Three sets of Serial Interface pins
 - Serial Interface 1
 - Snoop or Take-over connection of Serial Interface M
 - Two-to-one multiplexing of Serial Ports 1 and 2 to Serial Interface 2
- Floppy Disk Controller (FDC)
 - Programmable write protect
 - Supports FM and MFM modes
 - Supports Enhanced mode command for three-mode Floppy Disk Drive (FDD)
 - Perpendicular recording drive support for 2.88 MB
 - Burst and Non-Burst modes
 - Full support for IBM Tape Drive Register (TDR) implementation of AT and PS/2 drive types

Features (Continued)

- 16-byte FIFO
- Error-free handling of data overrun and underrun
- Software compatible with the PC8477, which contains a superset of the FDC functions in the μ DP8473, NEC μ PD765A/B and N82077
- High-performance digital separator
- Supports standard 5.25" and 3.5" FDDs
- Supports one FDD
- Supports fast tape drives (2 Mbps) and standard tape drives (1 Mbps, 500 Kbps and 250 Kbps)

■ Keyboard and Mouse Controller (KBC)

- 8-bit microcontroller, software compatible with 8042AH and PC87911
- Standard interface (60h, 64h, IRQ1 and IRQ12)
- Supports two external swappable PS/2 interfaces for keyboard and mouse
- Five programmable, dedicated, quasi-bidirectional I/O lines (Fast GA20/P21, KBRST/P20, P12, P16, P17)

General-Purpose I/O Module

■ 52 General-Purpose I/O (GPIO) Ports

- Individually assigned to either LPC or SMBus control
- 45 ports individually configured as input or output
- 7 output ports
- Programmable features for each output pin:
 - Drive type (open-drain, push-pull or TRI-STATE)
 - TRI-STATE on V_{DD} -fall detection for pins driving V_{DD} -supplied devices
- Programmable option for internal pull-up resistor on each input pin
- Lock option for the configuration and data of each output pin
- 16 GPIO ports generate $\overline{\text{IRQ}}/\text{SIOSMI}/\text{SIOSCI}$ for wake-up events, with individual:
 - Enable control
 - Polarity and edge/level selection
 - Debounce mechanism
- V_{SB} powered
- Low-cost external GPIO port extension via a serial bus
- I/O ports transactions routing to the GPIO port extension

■ Real-Time Clock

- DS1287, MC146818 and PC87911 compatible
- Battery-backed 242-byte CMOS RAM, in two banks (accessed through 70-71h and 72-73h)
- Selective lock mechanisms for the RTC RAM
- Y2K-compliant calendar, including century and automatic leap-year adjustment
- Time of day in seconds, minutes and hours, which allows a 12-hour or 24-hour format with optional adjustment for daylight saving time

- Separated SMBus access to RTC RAM and RTC Control D register
- Battery level measurement

Power Management

■ Supports ACPI Specification Revision 2.0b, July 27, 2000

■ System Wake-Up Control (SWC)

- Wake-up request on detection of:
 - Preprogrammed Keyboard or Mouse sequence
 - External modem ring from $\overline{\text{RI1}}$ or $\overline{\text{RI2}}$ on serial ports
 - Predetermined RTC date and time alarm
 - General-Purpose Input Events from up to 16 GPIO pins
 - IRQs of internal logical devices
- Optional routing of power-up request to $\overline{\text{SERIRQ}}$, $\overline{\text{SIOSMI}}$, $\overline{\text{SIOSCI}}$, $\overline{\text{PWBTOU}}$ and $\overline{\text{ONCTL}}$
- Routing control per input/output event combination
- Outputs enable/disable per event and system state combination (ACPI Sx states)
- Implements bank "b" of the ACPI registers
- Suspend modes via software emulation (control)
- Battery-backed event-logic configuration
- Power Button support, featuring:
 - On/Off control
 - Power-off, 4-second override
 - Power Button output
- Sleep Button support

■ Power Supply On/Off control

- Supports Legacy- and ACPI-compatible Power Button
- Direct power supply control in response to wake-up events
- Programmable Crowbar time-out for "On" request
- On/Off control via software emulation
- Power-fail recovery

■ Enhanced Power Management (PM), including:

- Special configuration registers for power down
- Reduced current leakage from pins
- Low-power CMOS technology
- Capability for disabling all modules

■ Keyboard Events

- Wake-up on any key
- Supports programmable 8-byte sequence "password" for Power Management
- Simultaneous recognition of three programmable keys (sequences): "Power", "Sleep" and "Resume"

■ Power Active Timers

- Two power-on, elapsed-time counters for the main (V_{DD}) and standby (V_{SB}) power supplies
- 32-bit counters, clocked by a 1-second clock
- V_{BAT} backed-up counters

Features (Continued)

■ Watchdog

- Compliant with *Watchdog Timer Hardware Requirements for Microsoft Windows .NET Server, April 2002*
- Autonomous system reset and programmable address line forcing on expiration of watchdog timer
- Generates a 100 ms pulse at $\overline{\text{WDO}}$ pin

Clocking, Supply and Package Information

■ Strap Input Controlled Operating Modes

- Base Address ($\overline{\text{BADDR}}$) for the PnP Index-Data register pair
- Input clock presence ($\overline{\text{CKIN48}}$) select
- X-Bus configuration ($\overline{\text{XCNF2-0}}$) select
- SMBus slave address ($\overline{\text{SMBSA}}$) select
- High frequency clock selection ($\overline{\text{HFCKS}}$)

■ Testability

- XOR tree structure
 - ❑ Includes all the device pins (except the supply pins, oscillator pins and CHASSIS pin)
 - ❑ Selected at power-up by strap input ($\overline{\text{TEST}}$)
- TRI-STATE device pins, selected at power-up by strap input ($\overline{\text{TRIS}}$)

■ Clocks

- LPC clock input (up to 33 MHz)
- ServerI/O modules clock: 48 MHz input or internal clock multiplier
- 32.768 KHz crystal
- On-chip low-frequency clock generator:
 - ❑ 32.768 KHz for RTC, System Wake-Up Control (SWC), Power Active timers and the high-frequency clock generator
 - ❑ Very low power consumption
 - ❑ V_{BAT} powered

- On-chip high-frequency clock generator:

- ❑ Based on the 32.768 KHz clock
- ❑ V_{SB} powered

- Clock outputs:

- ❑ LFCKOUT - 32.768 KHz or 1 Hz
- ❑ HFCKOUT - configurable up to 48 MHz. The default frequency 6, 10, 24 or 40 MHz, configurable by strap.

■ Protection

- All pins are 5V tolerant and back-drive protected (except the LPC bus pins)
- Separate battery pin that includes an internal UL protection resistor
- GPIO multiplexing configuration lock

■ Power Supply

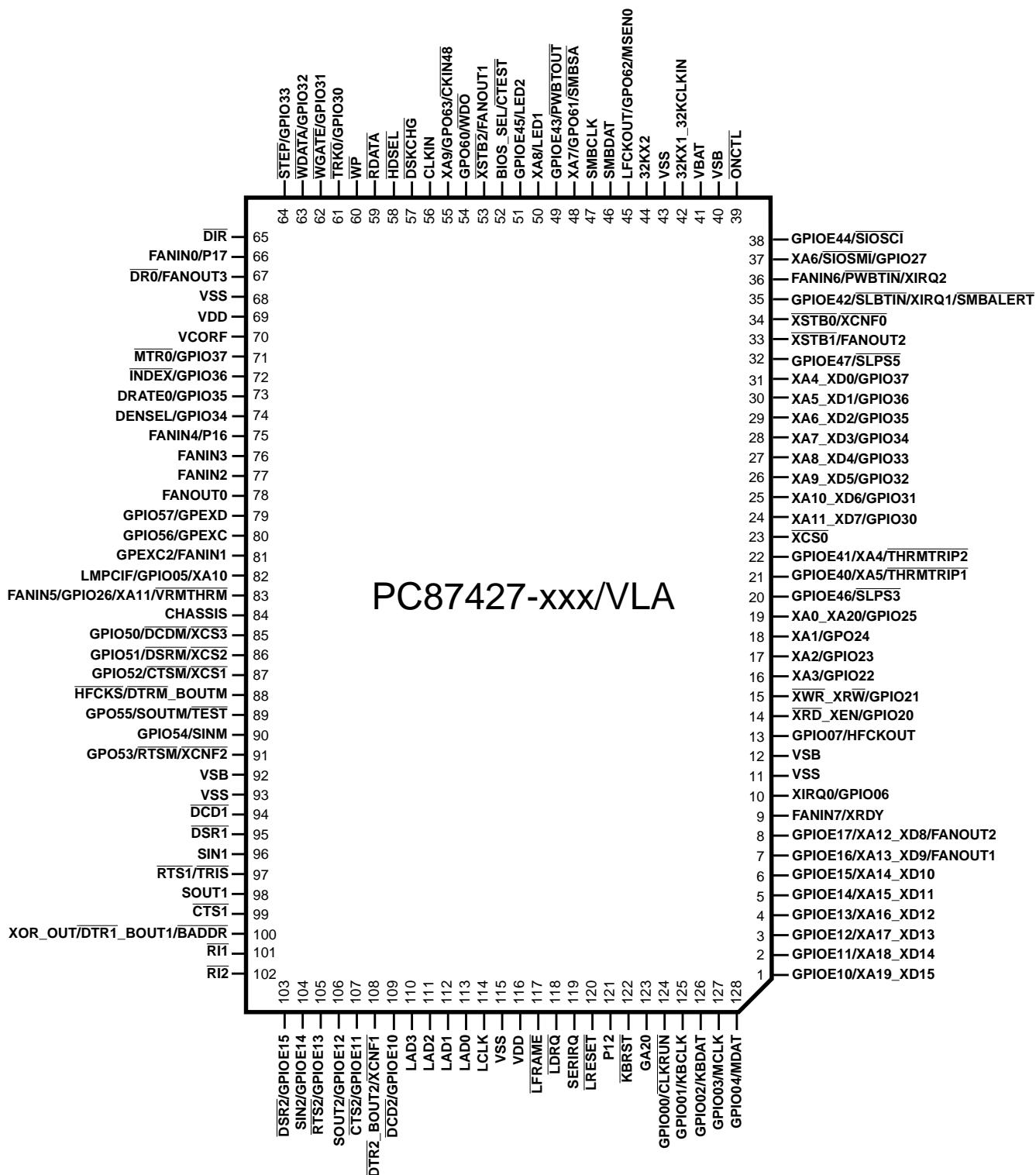
- 3.3V supply operation
- Separate pins for main (V_{DD}) and standby (V_{SB}) power supplies
- Backup battery input for RTC, SWC and Power Active timers
- Separate pin for core voltage filtering (V_{CORF})
- Reduced standby power consumption
- Very low power consumption for RTC and timers (0.9 μA typical) from backup battery

■ Package

- 128-pin PQFP

1.0 Signal/Pin Connection and Description

1.1 CONNECTION DIAGRAM



Plastic Quad Flatpack (PQFP), JEDEC
 Order Number PC87427-xxx/VLA
 See NS Package Number VLA128A

xxx = Three-character identifier for National data, keyboard ROM and/or customer identification code.

1.0 Signal/Pin Connection and Description (Continued)

1.2 BUFFER TYPES AND SIGNAL/PIN DIRECTORY

The signal DC characteristics of the pins described in Section 1.4 are denoted by buffer type symbols, which are defined in Table 1. The pin multiplexing information refers to two different types of multiplexing:

- Multiplexed, denoted by a slash (/) between pins in the diagram in Section 1.1. Pins are shared between two different functions. Each function is associated with different board connectivity. Normally, the function selection is determined by the board design and cannot be changed dynamically. The multiplexing options must be configured by the BIOS on power-up to comply with the board implementation.
- Multiple Mode, denoted by an underscore (_) between pins in the diagram in Section 1.1. Pins have two or more modes of operation within the same function. These modes are associated with the same external (board) connectivity. Mode selection can be controlled by the device driver through the registers of the functional block and does not require a special BIOS setup upon power-up. These pins are not considered multiplexed pins from the Server/I/O configuration perspective. The mode selection method (registers and bits), as well as the signal specification in each mode, are described within the functional description of the relevant functional block.

Table 1. Buffer Types

Symbol	Description
IN _{CS}	Input, CMOS compatible, with Schmitt Trigger
IN _{OSC}	Input, from crystal oscillator (not characterized)
IN _{PCI}	Input, PCI 3.3V
IN _{SM}	Input, SMBus compatible
IN _T	Input, TTL compatible
IN _{TS}	Input, TTL compatible, with Schmitt Trigger
IN _{ULR}	Input, power, resistor protected (not characterized)
O _{p/n}	Output, push-pull output buffer capable of sourcing <i>p</i> mA and sinking <i>n</i> mA
OD _n	Output, open-drain output buffer capable of sinking <i>n</i> mA
O _{OSC}	Output, to crystal oscillator (not characterized)
O _{PCI}	Output, PCI 3.3V
OD _{PCI}	Output, open-drain, PCI 3.3V
PWR	Power pin
GND	Ground pin

1.0 Signal/Pin Connection and Description (Continued)

1.3 PIN MULTIPLEXING

The table below shows only multiplexed pins, their associated functional blocks and the configuration bits for the selection of the multiplexed options used in the PC87427.

Table 2. Pin Multiplexing Configuration

Pin	Functional Block	Signal	Functional Block	Signal	Functional Block	Signal	Functional Block	Signal	Configuration Select
1	GPIO	GPIOE10	X-Bus	XA19_XD15					SIOCF3.XDATA16
2		GPIOE11		XA18_XD14					SIOCF3.XDATA16
3		GPIOE12		XA17_XD13					
4		GPIOE13		XA16_XD12					
5		GPIOE14		XA15_XD11					SIOCF3.XDATA16
6		GPIOE15		XA14_XD10					
7		GPIOE16		XA13_XD9	FMC	FANOUT1			SIOCF3.XDATA16 & SIOCFB.FANOUT1
8		GPIOE17		XA12_XD8		FANOUT2			SIOCF3.XDATA16 & SIOCFB.FANOUT2
9				XRDY		FANIN7			SIOCF4.XRDYMUX
10	GPIO	GPIO06		XIRQ0					SIOCF5.XIRQ0MUX
13		GPIO07	Clocks	HFCKOUT					SIOCF4.HFCKMUX
14		GPIO20	X-Bus	XRD_XEN					SIOCF4.NOXBUS
15		GPIO21		XWR_XRW					
16		GPIO22		XA3					
17		GPIO23		XA2					
18		GPO24		XA1					
19		GPIO25		XA0_XA20					
20		GPIOE46	SWC	SLPS3					SIOCF3.EXTSTMUX
21		GPIOE40		XA5	HMC	THRMTRIP1			SIOCF4.NOADDIR & SIOCFB.TRIP1
22		GPIOE41		XA4		THRMTRIP2			SIOCF4.NOADDIR & SIOCFB.TRIP2
24		GPIO30	X-Bus	XA11_XD7					SIOCF4.NOXBUS
25		GPIO31		XA10_XD6					
26		GPIO32		XA9_XD5					
27		GPIO33		XA8_XD4					
28		GPIO34		XA7_XD3					
29		GPIO35		XA6_XD2					
30		GPIO36		XA5_XD1					
31		GPIO37		XA4_XD0					
32		GPIOE47	SWC	SLPS5					SIOCF3.EXTSTMUX
33	X-Bus	XSTB1	FMC	FANOUT2					SIOCF5.XSTB1MUX
34		XSTB0	Straps	XCNF0					
35		XIRQ1	GPIO	GPIOE42	SWC	SLBTIN	SMBus	SMBALERT	SIOCF3.SLBTIMUX & SIOCF3.XIRQ1MUX
36		XIRQ2	FMC	FANIN6		PWBTIN			SIOCF3.PWBTIMUX & SIOCFB.FANIN6MUX
37		XA6	GPIO	GPIO27		SIOSMI			SIOCF3.SMIMUX & SIOCF4.NOADDIR
38				GPIOE44		SIOSCI			SIOCF3.SCIMUX

1.0 Signal/Pin Connection and Description (Continued)

Table 2. Pin Multiplexing Configuration (Continued)

Pin	Functional Block	Signal	Functional Block	Signal	Functional Block	Signal	Functional Block	Signal	Configuration Select
45	GPIO	GPO62	Clocks	LFCKOUT	FDC	MSEN0			SIOCF4.LFCKMUX
48		GPO61	X-Bus	XA7	Straps	SMBSA			SIOCF4.NOADDIR
49		GPIOE43		PWBTOUT					SIOCF3.PWBTOMUX
50	X-Bus	XA8	SWC	LED1					SIOCF4.NOADDIR
51	GPIO	GPIOE45		LED2					SIOCF3.LED2MUX
52	X-Bus	BIOS_SEL	Straps	CTEST					
53	X-Bus	XSTB2	FMC	FANOUT1					SIOCF5.XSTB2MUX
54	GPIO	GPO60	Watchdog	WDO					SIOCF2.WDOMUX
55		GPO63	X-Bus	XA9	Straps	CKIN48			SIOCF4.NOADDIR
61	GPIO	GPIO30	FDC	TRK0					SIOCF3.GP3AMUX
62		GPIO31		WGATE					
63		GPIO32		WDATA					
64		GPIO33		STEP					
66	FMC	FANIN0	KBC	P17					SIOCF2.P17MUX
67		FANOUT3		DR0					SIOCFB.FANOUT3
71	GPIO	GPIO37	FDC	MTR0					SIOCF3.GP3AMUX
72		GPIO36		INDEX					
73		GPIO35		DRATE0					
74		GPIO34		DENSEL					
75	FMC	FANIN4	KBC	P16					SIOCF2.P16MUX
79	GPIO	GPIO57	GPIO	GPEXD					SIOCF3.GPEXMUX
80		GPIO56		GPEXC					
81	FMC	FANIN1		GPEXC2					SIOCFB.FANIN1MUX & SIOCFD.GPEXC2MUX
82	X-Bus	XA10	HMC	LMPCIF	GPIO	GPIO05			SIOCF4.NOADDIR & SIOCFD.LMPCIF
83		XA11		VRMTHRM		GPIO26	FMC	FANIN5	SIOCF4.NOADDIR & SIOCFB.FANIN5
85		XCS3	Serial Interface M	DCDM		GPIO50			SIOCF3.SIMMUX & SIOCF5.XCS3MUX
86		XCS2		DSRM		GPIO51			SIOCF3.SIMMUX & SIOCF5.XCS2MUX
87		XCS1		CTSM		GPIO52			SIOCF3.SIMMUX & SIOCF5.XCS1MUX
88	Straps	HFCKS		DTRM_BOUTM					
89		TEST		SOUTM	GPIO	GPO55			SIOCF3.SIMMUX
90				SINM		GPIO54			
91	Straps	XCNF2		RTSM		GPO53			
97	Serial Interface 1	RTS1	Straps	TRIS					
100	Serial Interface 1	DTR1_BOUT1	Straps	BADDR	Testability	XOR_OUT			For XOR_OUT selection

1.0 Signal/Pin Connection and Description (Continued)

Table 2. Pin Multiplexing Configuration (Continued)

Pin	Functional Block	Signal	Functional Block	Signal	Functional Block	Signal	Functional Block	Signal	Configuration Select
103	GPIO	GPIOE15	Serial Interface 2	DSR2					SIOCFC.GP1AMUX
104		GPIOE14		SIN2					
105		GPIOE13		RTS2					
106		GPIOE12		SOUT2					
107		GPIOE11		CTS2					SIOCFC.GP1AMUX
108	Straps	XCNF1		DTR2_BOUT2					
109		GPIOE10		DCD2					SIOCFC.GP1AMUX
124		GPIO00	LPC	CLKRUN					SIOCF2.CLKRNMUX
125		GPIO01	KBC	KBCLK					SIOCF2.NOKBC
126		GPIO02		KBDAT					
127		GPIO03		MCLK					
128		GPIO04		MDAT					

1.4 DETAILED SIGNAL/PIN DESCRIPTIONS

This section describes all PC87427 signals.

1.4.1 LPC Interface

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description
LAD3-0 ¹	110-113	I/O	IN _{PCI} /O _{PCI}	V _{DD}	LPC Address-Data. Multiplexed command, address bidirectional data, and cycle status.
LCLK ¹	114	I	IN _{PCI}	V _{DD}	LPC Clock. Derived from the PCI clock (up to 33 MHz).
LFRAME ¹	117	I	IN _{PCI}	V _{DD}	LPC Frame. Low pulse indicates the beginning of a new LPC cycle or termination of a broken cycle.
LDRQ ¹	118	O	O _{PCI}	V _{DD}	LPC DMA Request. Encoded DMA request for LPC Interface.
LRESET ¹	120	I	IN _{PCI}	V _{DD}	LPC Reset. Derived from the PCI system reset.
SERIRQ ¹	119	I/O	IN _{PCI} /O _{PCI}	V _{DD}	Serial IRQ. The interrupt requests are serialized over a single pin, where each IRQ level is delivered during a designated time slot.
CLKRUN ¹	124	I/O	IN _{PCI} /OD _{PCI}	V _{DD}	Clock Run. Indicates that LCLK is going to be stopped and requests full-speed LCLK (same behavior as PCI CLKRUN).

1. This pin is neither 5-Volt tolerant nor back-drive protected.

1.4.2 SMBus (SMB) Interface

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description
SMBCLK	47	I/O	IN _{SM} /OD ₆	V _{SB}	SMBus Clock. An internal pull-up for this pin is optional.
SMBDAT	46	I/O	IN _{SM} /OD ₆	V _{SB}	SMBus Serial Data. An internal pull-up for this pin is optional.
SMBALERT	35	O	OD ₆	V _{SB}	SMBus Alert. SMBus Interrupt line. An internal pull-up for this pin is optional.

1.0 Signal/Pin Connection and Description (Continued)

1.4.3 X-Bus Extension

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description
$\overline{\text{XRD_XEN}}$	14	O	$O_{6/12}$	V_{SB}	Read. Active (low) level indicates a read cycle on the X-Bus. Enable. Active (high) level indicates valid data on the X-Bus.
$\overline{\text{XWR_XR\overline{W}}}$	15	O	$O_{14/14}$	V_{SB}	Write. Active (low) level indicates a write cycle on the X-Bus. Read/Write. A high level indicates a read cycle on the X-Bus; a low level indicates a write cycle on the X-Bus.
XA19_XD15 -XA12_XD8 XA11_XD7 -XA4_XD0	1-8, 24-31	I/O	$IN_{TS}/O_{4/8}$	V_{SB}	Multiplexed Data/Address Bus Lines. The XA11-4 address lines are multiplexed with the 8-bit data lines XD7-XD0. If the 16-bit data bus is selected, the XA19-12 address lines are multiplexed with data lines XD15-XD8.
XA11-1, XA0_XA20	83, 82, 55, 50, 48, 37, 21, 22, 16-18, 19	O	$O_{3/6}$	V_{SB}	Non-Multiplexed Address Bus Lines. The XA0 address line pin is the XA20 address line for XCSn configured to 16-bit data bus.
$\overline{\text{XSTB2-0}}$	53, 33-34	O	$O_{3/6}$	V_{SB}	Address Strokes. Controls the strobe of up to three external latches for the multiplexed address lines.
$\overline{\text{XCS3-0}}$	85-87, 23	O	$O_{14/14}$	V_{SB}	Chip Selects. Controls the selection of up to four devices residing on the X-Bus.
XRDY	9	I	IN_{TS}	V_{SB}	I/O Ready. Instructs the PC87427 to extend the access cycle.
XIRQ2-0	36-35, 10	I	IN_{TS}	V_{SB}	X-Bus Interrupt. Converted into serial interrupt by the Interrupt Serializer. The system configuration includes the interrupt number associated with this signal.
BIOS_SEL	52	O	$O_{3/6}$	V_{SB}	BIOS Select. BIOS image selections.

1.4.4 Serial Port Interfaces (SI1, SI2 and SIM)

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description
$\overline{\text{CTS1}}$	99	I	IN_{TS}	V_{DD}	Clear to Send. When low, indicates that the modem or other data transfer device is ready to exchange data.
$\overline{\text{CTS2}}$ $\overline{\text{CTSM}}$	107 87			V_{SB}	
$\overline{\text{DCD1}}$	94	I	IN_{TS}	V_{DD}	Data Carrier Detected. When low, indicates that the data transfer device, e.g., modem, has detected the data carrier.
$\overline{\text{DCD2}}$	109			V_{SB}	
$\overline{\text{DCDM}}$	85	O^1	$O_{14/14}$	V_{SB}	
$\overline{\text{DSR1}}$	95	I	IN_{TS}	V_{DD}	Data Set Ready. When low, indicates that the data transfer device, e.g., modem, is ready to establish a communications link.
$\overline{\text{DSR2}}$ $\overline{\text{DSRM}}$	103 86			V_{SB}	

1.0 Signal/Pin Connection and Description (Continued)

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description
DTR1_ BOUT1	100	O	O _{4/8}	V _{DD}	Data Terminal Ready. When low, indicates to the data transfer device, e.g., modem, that the UART is ready to establish a communications link. After a system reset, these pins provide the DTR function and set these signals to inactive high. Loopback operation holds them inactive. Baud Output. Provides the associated serial channel baud rate generator output signal if Test mode is selected, i.e., bit 7 of EXCR1 register is set.
DTR2_ BOUT2	108			V _{SB}	
DTRM_ BOUTM	88				
RI1	101	I	IN _{TS}	V _{DD}	Ring Indicator. When low, indicates that a telephone ring signal was received by the modem. These pins are monitored during V _{DD} power-off for wake-up event detection.
RI2	102			V _{SB}	
RTS1	97	O	O _{3/6}	V _{DD}	Request to Send. When low, indicates to the modem or other data transfer device that the corresponding UART is ready to exchange data. A system reset sets these signals to inactive high, and loopback operation holds them inactive.
RTS2 RTSM	105 91			V _{SB}	
SIN1	96	I	IN _{TS}	V _{DD}	Serial Input. Receives composite serial data from the communications link (peripheral device, modem or other data transfer device).
SIN2 SINM	104 90			V _{SB}	
SOUT1	98	O	O _{3/6}	V _{DD}	Serial Output. Sends composite serial data to the communications link (peripheral device, modem or other data transfer device). These signals are set active high after a system reset.
SOUT2 SOUTM	106 89			V _{SB}	

1. DCDM is an output signal due to its role in an exchange connection with an external BMC.

1.4.5 Fan Monitor & Control (FMC)

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description
FANIN0-7	66, 81, 77, 76, 75, 83, 36, 9	I	IN _{TS}	V _{DD}	Fan Inputs. Used to feed the fan's tachometer pulse to the Fan Speed Monitor.
FANOUT0	78	O	OD ₁₂ , O _{6/12}	V _{DD}	Fan Outputs. Pulse Width Modulation (PWM) signals, used to control the speed of cooling fans by controlling the voltage supplied to the fans motors.
FANOUT1	7				
	53				
FANOUT2	8				
	33				
FANOUT3	67				

1.0 Signal/Pin Connection and Description (Continued)

1.4.6 Health Monitoring & Control (HMC)

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description
LMPCIF	82	I/O	IN _{SM} /OD ₆	V _{SB}	LMPC Sensor Interface. Bidirectional, SensortPath proprietary interface signal to LMPC sensor device(s). An internal pull-up for this pin is optional.
THRMTRIP1-2	21, 22	I	IN _{TS}	V _{DD}	Thermal Trip Inputs. Indicates that a thermal trip from a CPU occurred.
VRMTHRM	83	I	IN _{TS}	V _{DD}	VRM Thermal Warning. Thermal warning from a VRM of a CPU.

1.4.7 Keyboard and Mouse Controller (KBC)

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description
KBCLK	125	I/O	IN _{TS} /OD ₁₄	V _{DD}	Keyboard Clock. Keyboard clock signal. An external pull-up resistor is required for PS/2 compliance. This pin is monitored during V _{DD} power-off for wake-up event detection.
KBDAT	126	I/O	IN _{TS} /OD ₁₄	V _{DD}	Keyboard Data. Keyboard data signal. An external pull-up resistor is required for PS/2 compliance. This pin is monitored during V _{DD} power-off for wake-up event detection.
MCLK	127	I/O	IN _{TS} /OD ₁₄	V _{DD}	Mouse Clock. Mouse clock signal. An external pull-up resistor is required for PS/2 compliance. This pin is monitored during V _{DD} power-off for wake-up event detection.
MDAT	128	I/O	IN _{TS} /OD ₁₄	V _{DD}	Mouse Data. Mouse data signal. An external pull-up resistor is required for PS/2 compliance. This pin is monitored during V _{DD} power-off for wake-up event detection.
KBRST	122	I/O	IN _T /OD ₈ , O _{4/8}	V _{DD}	KBD Reset. Keyboard reset (P20) quasi-bidirectional signal.
GA20	123	I/O	IN _T /OD ₈ , O _{4/8}	V _{DD}	Gate A20. KBC gate A20 (P21) quasi-bidirectional signal.
P12	121	I/O	IN _T /OD ₈ , O _{4/8}	V _{DD}	I/O Port. KBC quasi-bidirectional signal for general-purpose input and output (controlled by KBC firmware).
P16, P17	75, 66	I/O	IN _T /OD ₈ , O _{4/8}	V _{DD}	I/O Port. KBC quasi-bidirectional signal for general-purpose input and output (controlled by KBC firmware).

1.0 Signal/Pin Connection and Description (Continued)

1.4.8 General-Purpose I/O (GPIO)

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description
GPIO00	124	I/O	IN _{PCI} /O _{PCI}	V _{SB}	General-Purpose I/O Ports. Each pin is configured independently as input or I/O with or without static pull-up and with either open-drain or push-pull output type. The GPIOE <i>nn</i> pins have event detection capability.
GPIO01-04	125-128	I/O	IN _{TS} /O _{14/14}	V _{SB}	
GPIO05	82	I/O	IN _{TS} /O _{3/6}	V _{SB}	
GPIO06	10	I/O	IN _{TS} /O _{3/6}	V _{SB}	
GPIO07	13	I/O	IN _{TS} /O _{14/14}	V _{SB}	
GPIOE10, GPIOE12-15	1, 3-6	I/O	IN _{TS} /O _{3/6}	V _{SB}	
	109, 106-103		IN _{TS} /O _{14/14}		
GPIOE11	2	I/O	IN _{TS} /O _{3/6}	V _{SB}	
	107		IN _{TS} /O _{3/6}		
GPIOE16-17	7-8	I/O	IN _{TS} /O _{3/6}	V _{SB}	
GPIO20	14	I/O	IN _{TS} /O _{6/12}	V _{SB}	
GPIO21	15	I/O	IN _{TS} /O _{14/14}	V _{SB}	
GPIO22-23	16-17	I/O	IN _{TS} /O _{3/6}	V _{SB}	
GPO24	18	O	O _{3/6}	V _{SB}	General-Purpose Output Port.
GPIO25-27	19, 83, 37	I/O	IN _{TS} /O _{3/6}	V _{SB}	General-Purpose I/O Ports. Each pin is configured independently as input or I/O with or without static pull-up and with either open-drain or push-pull output type. The GPIOE <i>nn</i> pins have event detection capability.
GPIO37,35-31	31,29-25	I/O	IN _{TS} /O _{4/8}	V _{SB}	
	71, 73- 74, 64-62		IN _{TS} /O _{6/12}	V _{DD}	
GPIO36,30	30, 24	I/O	IN _{TS} /O _{4/8}	V _{SB}	
	72, 61		IN _{TS} /O _{3/6}	V _{DD}	
GPIOE40-44	21-22, 35, 49, 38	I/O	IN _{TS} /O _{3/6}	V _{SB}	
GPIOE45	51	I/O	IN _{TS} /O _{14/14}	V _{SB}	
GPIOE46-47	20, 32	I/O	IN _{TS} /O _{3/6}	V _{SB}	
GPIO50-52	85-87	I/O	IN _{TS} /O _{14/14}	V _{SB}	
GPO53	91	O	O _{3/6}	V _{SB}	General-Purpose Output Port.
GPIO54	90	I/O	IN _{TS} /O _{3/6}	V _{SB}	General-Purpose I/O Port. The pin is configured independently as input or I/O with or without static pull-up and with either open-drain or push-pull output type.
GPO55	89	O	O _{3/6}	V _{SB}	General-Purpose Output Port.
GPIO56-57	80-79	I/O	IN _{TS} /O _{14/14}	V _{SB}	General-Purpose I/O Ports. Each pin is configured independently as input or I/O with or without static pull-up and with either open-drain or push-pull output type. The GPIOE <i>nn</i> pins have event detection capability.

1.0 Signal/Pin Connection and Description (Continued)

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description
GPO60-63	54,48, 45,55	O	O _{3/6}	V _{SB}	General-Purpose Output Ports.
GPEXD	79	I/O	IN _{TS} /O _{14/14}	V _{SB}	General-Purpose I/O Extension Data.
GPEXC	80	O	O _{14/14}	V _{SB}	General-Purpose I/O Extension Clock.
GPEXC2	81	O	O _{14/14}	V _{SB}	General-Purpose I/O Extension Clock 2.

1.4.9 Floppy Disk Controller (FDC)

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description
DENSEL	74	O	OD ₁₂ ,O _{6/12}	V _{DD}	Density Select. Indicates that either a high FDC density data rate (500 Kbps, 1 Mbps or 2 Mbps) or a low density data rate (250 or 300 Kbps) is selected.
DIR	65	O	OD ₁₂ ,O _{6/12}	V _{DD}	Direction. Determines the direction of the Floppy Disk Drive (FDD) head movement (active = step in; inactive = step out) during a seek operation.
DR0	67	O	OD ₁₂ ,O _{6/12}	V _{DD}	Drive Select. Controlled by bit 0 of the Digital Output Register (DOR).
DRATE0	73	O	OD ₁₂ ,O _{6/12}	V _{DD}	Data Rate. Reflects the value of bit 0 of the Configuration Control Register (CCR) or the Data Rate Select Register (DSR), whichever was written to last.
DSKCHG	57	I	IN _{TS}	V _{DD}	Disk Change. Indicates if the drive door was opened.
HDSEL	58	O	OD ₁₂ ,O _{6/12}	V _{DD}	Head Select. Determines which side of the FDD is accessed. Active low selects side 1; inactive selects side 0.
INDEX	72	I	IN _{TS}	V _{DD}	Index. Indicates the beginning of an FDD track.
MSEN0	45	I	IN _{TS}	V _{DD}	Automatic Media Sense. Identifies the media type of the floppy disk in drives 1 and 0 (if the drives support this protocol).
MTR0	71	O	OD ₁₂ ,O _{6/12}	V _{DD}	Motor Select. Motor enable lines for drives 0.
RDATA	59	I	IN _{TS}	V _{DD}	Read Data. Raw serial input data stream read from the FDD.
STEP	64	O	OD ₁₂ ,O _{6/12}	V _{DD}	Step. Sends pulses to the disk drive at a software programmable rate to move the head during a seek operation.
TRK0	61	I	IN _{TS}	V _{DD}	Track 0. Indicates to the controller that the head of the selected floppy disk drive is at track 0.
WDATA	63	O	OD ₁₂ ,O _{6/12}	V _{DD}	Write Data. Carries out the pre-compensated serial data that is written to the FDD. Pre-compensation is software selectable.
WGATE	62	O	OD ₁₂ ,O _{6/12}	V _{DD}	Write Gate. Enables the write circuitry of the selected FDD.
WP	60	I	IN _{TS}	V _{DD}	Write Protected. Indicates that the disk in the selected drive is write protected.

1.0 Signal/Pin Connection and Description (Continued)

1.4.10 System Wake-Up Control (SWC)

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description															
GPIOE17-16	8-7	I	IN _{TS}	V _{SB}	Wake-up Inputs. Generate a wake-up event or an interrupt. These pins have programmable debounce protection.															
GPIOE15-10	103-107, 109																			
GPIOE11-10	2-1																			
GPIOE40-47	21-22, 35, 49, 38, 51, 20, 32																			
RI1 RI2	101 102	I	IN _{TS}	V _{SB}	Ring Indicator Wake-up. When low, generates a wake-up event or an interrupt, indicating that a telephone ring signal was received by the modem. When RI functionality is not required, an internal pull-up resistor allows this pin to be left floating.															
KBCLK	125	I	IN _{TS}	V _{SB}	Keyboard Clock Wake-up. Generates a wake-up event or an interrupt, indicating a change in the keyboard clock signal.															
KBDAT	126	I	IN _{TS}	V _{SB}	Keyboard Data Wake-up. Generates a wake-up event or an interrupt, indicating a change in the keyboard data signal.															
MCLK	127	I	IN _{TS}	V _{SB}	Mouse Clock Wake-up. Generates a wake-up event or an interrupt, indicating a change in the mouse clock signal.															
MDAT	128	I	IN _{TS}	V _{SB}	Mouse Data Wake-up. Generates a wake-up event or an interrupt, indicating a change in the mouse data signal.															
PWBTIN	36	I	IN _{TS}	V _{SB}	Power Button In. Active (low) level indicates a user request to turn the power on or off. This pin has debounce protection.															
PWBTOUT	49	O	OD ₆	V _{SB}	Power Button Out. Output for the chip-set Power Button input.															
SLBTIN	35	I	IN _{TS}	V _{SB}	Sleep Button In. Active (low) level indicates a user request to enter or exit Sleep mode. This pin has debounce protection.															
SLPS3, SLPS5	20 32	I	IN _{TS}	V _{SB}	Sleep State 3 to 5. Active (low) level indicates the system is in one of the sleep states S3, S4 or S5. These signals are generated by an external ACPI controller. Pins <table><tr><th>SLPS3</th><th>SLPS5</th><th>Functionality</th></tr><tr><td>1</td><td>1</td><td>Working state (S0) or sleep states S1 or S2</td></tr><tr><td>0</td><td>1</td><td>Sleep state S3</td></tr><tr><td>0</td><td>0</td><td>Sleep states S4 or S5</td></tr><tr><td>1</td><td>0</td><td>Illegal combination</td></tr></table>	SLPS3	SLPS5	Functionality	1	1	Working state (S0) or sleep states S1 or S2	0	1	Sleep state S3	0	0	Sleep states S4 or S5	1	0	Illegal combination
SLPS3	SLPS5	Functionality																		
1	1	Working state (S0) or sleep states S1 or S2																		
0	1	Sleep state S3																		
0	0	Sleep states S4 or S5																		
1	0	Illegal combination																		
SIOSCI	38	O	OD ₆	V _{SB}	System Control Interrupt. Active (low) level indicates that a wake-up event occurred, causing the system to exit its current sleep state.															
SIOSMI	37	O	OD ₆	V _{SB}	System Management Interrupt. Active (low) level indicates that an SMI occurred.															
ONCTL	39	O	OD ₆	V _{SB}	Power Supply On/Off Control. Active level (low) indicates that the power should be turned on. An external pull-up resistor is required															
LED1, LED2	50, 51	O	O _{14/14}	V _{SB}	LED Drives. These outputs can be connected directly to LED devices. They can be configured, with programmable blink rate for all LEDs, as one dual-colored LED or two single-colored LEDs.															
CHASSIS	84	I	IN _{CS}	V _{PP} ¹	Chassis Intrusion Input. Any change of this pin sets the intrusion detection. For correct operation, this pin must be tied to V _{SS} when it is not used.															

1. Internal V_{PP} is based on V_{SB} and V_{BAT}.

1.0 Signal/Pin Connection and Description (Continued)

1.4.11 Watchdog

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description
$\overline{\text{WDO}}$	54	O	O _{3/6}	V _{SB}	Watchdog Out. An active pulse (low) of a fixed width; it is generated when a watchdog time-out occurs.

1.4.12 Clocks

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description
32KX1_32KCLKIN ¹	42	I	IN _{OSC}	V _{PP}	32.768 KHz Crystal Input. Input from external crystal oscillator circuitry. 32.768 KHz Clock Oscillator Input. Input from external clock oscillator device. ²
32KX2 ³	44	O	O _{OSC}	V _{PP}	32.768 KHz Crystal Oscillator Output. Output to external crystal oscillator circuitry.
LFCKOUT	45	O	O _{3/6}	V _{SB}	Low Frequency Clock Output. The Real-Time Clock frequency (32.768 KHz), or a 1 Hz clock output.
CLKIN	56	I	IN _{TS}	V _{SB} ⁴	Clock Input. 48 MHz for the Legacy functions, or no input clock.
HFCKOUT	13	O	O _{14/14}	V _{SB}	High Frequency Clock Output. Clock output for system use.

1. This pin is not 5-volt tolerant.
2. If the input clock is in TRI-STATE while V_{SB} is off, it is recommended to connect an external 10 K Ω pull-down resistor to this pin.
3. This pin is neither 5-volt tolerant nor back-drive protected.
4. The CLKIN signal source can be V_{DD} powered.

1.4.13 Configuration Straps

Note: All external pull-down resistors must be connected to V_{SS}.

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description
$\overline{\text{BADDR}}$	100	I	IN _{TS}	V _{DD}	Base Address. Sampled at V _{DD} Power-Up reset to determine the base address of the configuration Index-Data register pair, as follows: No pull-down resistor: 2Eh-2Fh 10 K Ω ¹ external pull-down resistor: 4Eh-4Fh
$\overline{\text{TRIS}}$	97	I	IN _{TS}	V _{DD}	TRI-STATE Device. Sampled at V _{DD} Power-Up reset to force the device to float all its output and I/O pins, as follows: No pull-down resistor: Pins active 10 K Ω ¹ external pull-down resistor: Pins floating
$\overline{\text{CKIN48}}$	55	I	IN _{TS}	V _{SB}	CLKIN 48 MHZ. Sampled at V _{SB} Power-Up reset to determine the presence of the 48 MHz input clock at the CLKIN pin, as follows: No pull-down resistor: No clock 10 K Ω external pull-down resistor: 48 MHz clock

1.0 Signal/Pin Connection and Description (Continued)

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description
$\overline{\text{HFCKS}}$	88	I	IN _{TS}	V _{SB}	High Frequency Clock Selection. Sampled at V _{SB} Power-Up reset to determine the high frequency clock selection, as follows: For $\overline{\text{CKIN48}}=0$: No pull-down resistor: 40 MHz 10 K Ω ¹ external pull-down resistor: 10 MHz For $\overline{\text{CKIN48}}=1$: No pull-down resistor: 24 MHz 10 K Ω ¹ external pull-down resistor: 6 MHz
$\overline{\text{XCNF2-0}}$	91, 108, 34	I	IN _{TS}	V _{SB}	X-Bus Default Configuration. Sampled at V _{SB} Power-Up reset to set the configuration of the X-Bus transactions. Pins 2 1 0 Functionality 1 1 x: No BIOS 1 0 1: 16-bit data BIOS, XSTB0 only 1 0 0: 16-bit data BIOS, XSTB0 and XSTB1 0 1 1: 8-bit data BIOS, XA11-4 multiplexed, XRDY disabled 0 1 0: 8-bit data BIOS, XA11-4 multiplexed, XRDY enabled 0 0 1: 8-bit data BIOS, XA11-4 direct, XRDY disabled 0 0 0: 8-bit data BIOS, XA11-4 direct, XRDY enabled Pulled to 1 by internal resistor or set to 0 by external 10 K Ω ¹ pull-down resistor.
$\overline{\text{SMBSA}}$	48	I	IN _{TS}	V _{SB}	SMBus Slave Address. Sampled at V _{SB} Power-Up reset to determine the slave address of the device on SMBus, as follows: No pull-down resistor: D8h, D9h 10 K Ω external pull-down resistor: 60h, 61h
$\overline{\text{TEST}}$	89	I	IN _{TS}	V _{DD}	XOR Tree Test Mode. Sampled at V _{DD} Power-Up reset to force the device pins into a XOR tree configuration. No pull-down resistor (default): Normal device operation 10 K Ω ¹ external pull-down resistor: Pins configured as XOR tree. When $\overline{\text{TEST}}$ is set to 0 (by an external pull-down resistor), $\overline{\text{TRIS}}$ must be 1 (left unconnected).
$\overline{\text{CTEST}}$	52	I	IN _{TS}	V _{SB}	Complementary Test Mode. Sampled at V _{SB} Power-Up reset to set the device to Test Mode No pull-down resistor: Normal Operation mode 10 K Ω external pull-down resistor: Test Mode

1. Because the strap function is multiplexed with the Serial Port pins, a CMOS transceiver device is recommended for Serial Port functionality; in this case, the value of the external pull-down resistor is 10 K Ω . If, however, a TTL transceiver device is used, the value of the external pull-down resistor must be 470 Ω , and since the Serial Port pins are not able to drive this load, the external pull-down resistor must be disconnected t_{PLV} after V_{DD} power-up (see "Reset Timing" on page 27).

1.4.14 Testability

Signal	Pin(s)	I/O	Buffer Type	Power Well	Description
XOR_OUT	100	O	O _{4/8}	V _{DD}	XOR Tree Output. All the device pins (except power pins) are internally connected in a XOR tree structure.

1.0 Signal/Pin Connection and Description (Continued)

1.4.15 Power and Ground

Signal	Pin(s)	I/O	Buffer Type	Description
V _{SS}	11, 43, 68, 93, 115	I	GND	Ground. Serves for both on-chip logic, output drivers and back-up battery circuit.
V _{DD}	69, 116	I	PWR	Digital 3.3V Power Supply. Serves as power supply for the legacy peripherals and the LPC Interface.
V _{SB}	12, 40, 92	I	PWR	Standby Digital 3.3V Power Supply. Used for the SMBus and X-Bus interfaces, the GPIO ports and the clock generator. When active, it also powers the RTC and the SWC.
V _{CORF}	70	I/O	PWR	On-Chip Core Power Converter Filter. Used by the on-chip core power converter which powers the core logic of all the device modules. An external 1μF ceramic filter capacitor must be connected between this pin and V _{SS} .
V _{BAT}	41	I	IN _{ULR}	Battery Power Supply. When V _{SB} is off, this supply provides battery back-up to the SWC registers, the RTC and the 32 KHz crystal oscillator. The pin is connected to the internal logic through a series resistor for UL-compliant protection.

1.5 INTERNAL PULL-UP AND PULL-DOWN RESISTORS

The signals listed in Table 3 have internal pull-up (PU) and/or pull-down (PD) resistors. The internal resistors are optional for those signals indicated as "Programmable". See Section 2.3 on page 25 for the values of each resistor type.

Table 3. Internal Pull-Up and Pull-Down Resistors

Signal	Pin(s)	Power Well	Type	Comments
Keyboard and Mouse Controller (KBC)				
P12, P16, P17	121, 75, 66	V _{DD}	PU ₃₀	
SMBus (SMB) Interface				
SMBCLK	47	V _{SB}	PU ₃₀	Programmable ¹
SMBDAT	46	V _{SB}	PU ₃₀	Programmable ¹
SMBALERT	35	V _{SB}	PU ₃₀	Programmable ¹
Health Monitoring and Control (HMC)				
LMPCIF	82	V _{SB}	PU _{1K25}	Programmable ²
THRMTRIP1, THRMTRIP2	21, 22	V _{DD}	PU ₃₀	
VRMTHRM	83	V _{DD}	PU ₃₀	
System Wake-Up Control (SWC)				
PWBTIN	36	V _{SB}	PU ₃₀	
SLBTIN	35	V _{SB}	PU ₃₀	
PWBTOUT	49	V _{SB}	PU ₃₀	Note ³
SIOSMI	37	V _{SB}	PU ₃₀	
SIOSCI	38	V _{SB}	PU ₃₀	

1.0 Signal/Pin Connection and Description (Continued)

Table 3. Internal Pull-Up and Pull-Down Resistors (Continued)

Signal	Pin(s)	Power Well	Type	Comments
$\overline{\text{RI1}}$	101	V_{SB}	PU ₉₀	Pin can be left Not Connected
$\overline{\text{RI2}}$	102	V_{SB}	PU ₉₀	Pin can be left Not Connected
General-Purpose Input/Output (GPIO) Ports				
GPIO00-04, 06-07	124-128, 10, 13	V_{SB} or V_{DD}	PU ₃₀	Programmable
GPIO05	82	V_{SB}	PU _{1K25}	Programmable
GPIOE10-15	1-6	V_{SB}	PU ₃₀	Programmable
	109, 107-103			
GPIOE16-17	7, 8	V_{SB}	PU ₃₀	Programmable
GPIO20-27	14-19, 83, 37	V_{SB}	PU ₃₀	Programmable
GPIO30-37	61-64, 74, 73-71	V_{SB}	PU ₃₀	Programmable
GPIOE40-47	21-22, 35, 49, 38, 51, 20, 32	V_{SB}	PU ₃₀	Programmable
GPIO50-57	85-87, 91-89, 80-79	V_{SB}	PU ₃₀	Programmable ⁴
GPO60-63	54, 48, 45, 55	V_{SB}	PU ₃₀	Programmable
Strap Configuration				
BADDR	100	V_{DD}	PU ₃₀	Strap ⁵
TRIS	97	V_{DD}	PU ₃₀	Strap ⁵
CKIN48	55	V_{SB}	PU ₃₀	Strap ⁶
XCNF2-0	91, 108, 34	V_{SB}	PU ₃₀	Strap ⁶
SMBSA	48	V_{SB}	PU ₃₀	Strap ⁶
HFCKS	88	V_{SB}	PU ₃₀	Strap ⁶
TEST	89	V_{DD}	PU ₃₀	Strap ⁵
CTEST	52	V_{SB}	PU ₃₀	Strap ⁶

1. Default at reset: disabled.
2. Default at reset: enabled.
3. Disabled when V_{DD} is off.
4. Disabled during V_{SB} Power-Up reset.
5. Active only during V_{DD} Power-Up reset.
6. Active only during V_{SB} Power-Up reset.

2.0 Device Characteristics

2.1 GENERAL DC ELECTRICAL CHARACTERISTICS

2.1.1 Recommended Operating Conditions

Symbol	Parameter	Min	Typ	Max	Unit
V _{DD}	Supply Voltage	3.0	3.3	3.6	V
V _{SB}	Standby Voltage	3.0	3.3	3.6	V
V _{BAT}	Battery Backup Supply Voltage	2.4	3.0	3.6	V
T _A	Operating Temperature	0		+70	°C

2.1.2 Absolute Maximum Ratings

Absolute maximum ratings are values beyond which damage to the device may occur. Unless otherwise specified, all voltages are relative to ground.

Symbol	Parameter	Conditions	Min	Max	Unit
V _{SUP}	Supply Voltage ¹		-0.5	+4.1	V
V _I	Input Voltage	All other pins	-0.5	5.5	V
		LCLK, LAD3-0, LFRAME, LRESET, SERIRQ, CLKRUN, 32KX1_32KCLKIN	-0.5	V _{DD} + 0.5	V
V _O	Output Voltage	All other pins	-0.5	5.5	V
		LAD3-0, LDRQ, SERIRQ, CLKRUN, 32KX2	-0.5	V _{DD} + 0.5	V
T _{STG}	Storage Temperature		-65	+165	°C
P _D	Power Dissipation			1	W
T _L	Lead Temperature Soldering (10 s)			+260	°C
	ESD Tolerance	C _{ZAP} = 100 pF R _{ZAP} = 1.5 KΩ ²	2000		V
MCRS	Battery Maximum Safe Reverse Current	V _{SB} = 3.63V R _{UL} ³ = 1.6KΩ	2.27 ⁴		mA

1. V_{SUP} is V_{DD}, V_{SB} or V_{BAT}.

2. Value based on test complying with RAI-5-048-RA human body model ESD testing.

3. Minimum value of internal protection resistor.

4. For batteries with lower MCRS it is necessary to connect a series resistor between the battery and VBAT pin, with resistance: R=(3.63V/MCRS)-1.6 KΩ.

2.0 Device Characteristics (Continued)

2.1.3 Capacitance

Symbol	Parameter	Min ²	Typ ¹	Max ²	Unit
C _{IN}	Input Pin Capacitance		4	5	pF
C _{IN1}	Clock Input Capacitance ³	5	8	12	pF
C _{IO}	I/O Pin Capacitance		8	10	pF
C _O	Output Pin Capacitance		6	8	pF

1. T_A = 25°C, f = 1 MHz.

2. Not tested. Guaranteed by characterization.

3. LCLK, CLKIN.

2.1.4 Power Consumption under Recommended Operating Conditions

Symbol	Parameter	Conditions ¹	Typ	Max	Unit
I _{DD}	V _{DD} Average Main Supply Current	V _{IL} = 0.5V, V _{IH} = 2.4V No Load	14	20	mA
I _{DDL}	V _{DD} Quiescent Main Supply Current in Low Power Mode ²	V _{IL} = V _{SS} , V _{IH} = V _{DD} No Load	0.5	0.8	mA
I _{SB}	V _{SB} Average Main Supply Current	V _{IL} = 0.5V, V _{IH} = 2.4V No Load	21	30	mA
I _{SBL}	V _{SB} Quiescent Main Supply Current in Low Power Mode ²	V _{IL} = V _{SS} , V _{IH} = V _{SB} No Load	5	8	mA
I _{BAT}	V _{BAT} Battery Supply Current	V _{DD} , V _{SB} = 0V, V _{BAT} = 3V	0.9	1.5	μA

1. All parameters specified for 0° C ≤ T_A ≤ 70° C; V_{DD} and V_{SB} = 3.3V ±10%, unless otherwise specified.

2. All the modules disabled; clock outputs disabled; no LPC or SMBus activity.

2.1.5 Voltage Thresholds

Symbol	Parameter ¹	Min ²	Typ	Max ²	Unit
V _{DDON}	V _{DD} Detected as Power-on	2.3	2.6	2.9	V
V _{DDOFF}	V _{DD} Detected as Power-off	2.2	2.5	2.8	V
V _{DDHY}	V _{DD} Hysteresis (V _{DDON} – V _{DDOFF})	50			mV
V _{SBON}	V _{SB} Detected as Power-on	2.3	2.6	2.9	V
V _{SBOFF}	V _{SB} Detected as Power-off	2.2	2.5	2.8	V
V _{SBHY}	V _{SB} Hysteresis (V _{SBON} – V _{SBOFF})	50			mV
V _{BATDTC}	Battery Detected	1.0		1.2	V
V _{LOWBAT}	Low Battery Voltage	1.3		1.9	V

1. All parameters specified for 0° C ≤ T_A ≤ 70° C.

2. Not tested. Guaranteed by characterization.

2.0 Device Characteristics (Continued)

2.2 DC CHARACTERISTICS OF PINS, BY I/O BUFFER TYPES

The following tables summarize the DC characteristics of all device pins described in *Section 1.2 on page 6*. The characteristics describe the general I/O buffer types defined in Table 1 on page 6. For exceptions, refer to Section 2.2.10 on page 24. The DC characteristics of the LPC Interface meet the PCI Local Bus Specification (*Rev 2.2 December 18, 1998*) for 3.3V DC signaling. The DC characteristics of the SMBus Interface meet the SMBus (*Rev 1.1 Dec. 11, 1998*) and SMBus (*Rev. 2.0 Aug. 2000*) specifications for on-board devices.

2.2.1 Input, CMOS Compatible with Schmitt Trigger

Symbol: IN_{CS}

Symbol	Parameter	Conditions	Min	Max	Unit
V_{IH}	Input High Voltage		$0.75 V_{SUP}^1$	5.5^2	V
V_{IL}	Input Low Voltage		-0.5^1	1.1	V
V_{HY}	Input Hysteresis		500^3		mV
I_{IL}	Input Leakage Current	$0 < V_{IN} < V_{SUP}$		$\pm 1^4$	μA

1. V_{SUP} is V_{DD} , V_{SB} or V_{PP} according to the input power well.

2. Not tested. Guaranteed by design.

3. Not tested. Guaranteed by characterization.

4. Maximum 10 μA for all pins together. Not tested. Guaranteed by characterization.

2.2.2 Input, PCI 3.3V

Symbol: IN_{PCI}

Symbol	Parameter	Conditions	Min	Max	Unit
V_{IH}	Input High Voltage		$0.5 V_{DD}$	$V_{DD} + 0.5^1$	V
V_{IL}	Input Low Voltage		-0.5^1	$0.3 V_{DD}$	V
I_{IL}^2	Input Leakage Current	$0 < V_{IN} < V_{DD}$		$\pm 1^3$	μA

1. Not tested. Guaranteed by design.

2. Input leakage current includes the output leakage of the bidirectional buffers with TRI-STATE outputs.

3. Maximum 10 μA for all pins together. Not tested. Guaranteed by characterization.

2.2.3 Input, SMBus Compatible

Symbol: IN_{SM}

Symbol	Parameter	Conditions	Min	Max	Unit
V_{IH}	Input High Voltage		1.4	5.5^1	V
V_{IL}	Input Low Voltage		-0.5^1	0.8	V
I_{IL}^2	Input Leakage Current	$0 < V_{IN} < V_{SB}$		$\pm 1^3$	μA

1. Not tested. Guaranteed by design.

2. Input leakage current includes the output leakage of the bidirectional buffers with TRI-STATE outputs.

3. Maximum 10 μA for all pins together. Not tested. Guaranteed by characterization.

2.0 Device Characteristics (Continued)

2.2.4 Input, TTL Compatible

Symbol: IN_T

Symbol	Parameter	Conditions	Min	Max	Unit
V_{IH}	Input High Voltage		2.0	5.5 ¹	V
V_{IL}	Input Low Voltage		-0.5 ¹	0.8	V
I_{IL}^2	Input Leakage Current	$0 < V_{IN} < V_{SUP}^3$		$\pm 1^4$	μA

1. Not tested. Guaranteed by design.
2. Input leakage current includes the output leakage of the bidirectional buffers with TRI-STATE outputs.
3. V_{SUP} is V_{DD} , V_{SB} or V_{PP} according to the input power well.
4. Maximum 10 μA for all pins together. Not tested. Guaranteed by characterization.

2.2.5 Input, TTL Compatible with Schmitt Trigger

Symbol: IN_{TS}

Symbol	Parameter	Conditions	Min	Max	Unit
V_{IH}	Input High Voltage		2.0	5.5 ¹	V
V_{IL}	Input Low Voltage		-0.5 ¹	0.8	V
V_{HY}	Input Hysteresis		250 ²		mV
I_{IL}^3	Input Leakage Current	$0 < V_{IN} < V_{SUP}^4$		$\pm 1^5$	μA

1. Not tested. Guaranteed by design.
2. Not tested. Guaranteed by characterization.
3. Input leakage current includes the output leakage of the bidirectional buffers with TRI-STATE outputs.
4. V_{SUP} is V_{DD} , V_{SB} or V_{PP} according to the input power well.
5. Maximum 10 μA for all pins together. Not tested. Guaranteed by characterization.

2.2.6 Output, TTL Compatible Push-Pull Buffer

Symbol: $O_{p/n}$

Output, TTL Compatible, rail-to-rail Push-Pull buffer that is capable of sourcing p mA and sinking n mA

Symbol	Parameter	Conditions	Min	Max	Unit
V_{OH}	Output High Voltage	$I_{OH} = -p$ mA	2.4		V
		$I_{OH} = -50$ μA	$V_{SUP} - 0.2^1$		V
V_{OL}	Output Low Voltage	$I_{OL} = n$ mA		0.4	V
		$I_{OL} = 50$ μA		0.2	V

1. V_{SUP} is V_{DD} , V_{SB} or V_{PP} according to the output power well.

2.0 Device Characteristics (Continued)

2.2.7 Output, Open-Drain Buffer

Symbol: OD_n

Output, TTL Compatible Open-Drain output buffer capable of sinking n mA. Output from these signals is open-drain and is never forced high.

Symbol	Parameter	Conditions	Min	Max	Unit
V_{OL}	Output Low Voltage	$I_{OL} = n \text{ mA}$		0.4	V
		$I_{OL} = 50 \mu\text{A}$		0.2	V

2.2.8 Output, PCI 3.3V

Symbol: O_{PCI}

Symbol	Parameter	Conditions	Min	Max	Unit
V_{OH}	Output High Voltage	$I_{out} = -500 \mu\text{A}$	$0.9 V_{DD}$		V
V_{OL}	Output Low Voltage	$I_{out} = 1500 \mu\text{A}$		$0.1 V_{DD}$	V

2.2.9 Output, Open-Drain, PCI 3.3V

Symbol: OD_{PCI}

Symbol	Parameter	Conditions	Min	Max	Unit
V_{OL}	Output Low Voltage	$I_{out} = 1500 \mu\text{A}$		$0.1 V_{DD}$	V

2.2.10 Exceptions

1. All pins are 5-Volt tolerant except for the pins with PCI (IN_{PCI} , O_{PCI}) buffer types.
2. All pins are back-drive protected except for the pins with PCI (IN_{PCI} , O_{PCI}) and oscillator (O_{OSC}) buffer types.
3. The following pins have an internal static pull-up resistor (when enabled) and therefore may have leakage current to V_{SUP} (when $V_{IN} = 0$): P12, P16, P17, SMBCLK, SMBDAT, SMBALERT, PWBTTIN, SLBTIN, PWBTOU, SIOSMI, SIOSCI, GPIO00-07, GPIOE10-17, GPIO20-27, GPIO30-37, GPIOE40-47, GPO50-57 and GPIO60-63.
4. The following strap pins have an internal static pull-up resistor enabled during Power-Up reset and therefore may have leakage current to V_{SS} (when $V_{IN} = V_{SUP}$): BADDR, TRIS, CKIN48, XCNF2-0, SMBSA, HFCKS, CTEST and TEST.
5. I_{OH} is valid for a GPIO pin only when it is not configured as open-drain.

2.2.11 Terminology

Back-Drive Protection. A pin that is back-drive protected does not sink current into the supply when an input voltage higher than the supply, but below the pin's maximum input voltage, is applied to the pin. This is true even when the supply is inactive. Note that active pull-up resistors and active output buffers are typically not back-drive protected.

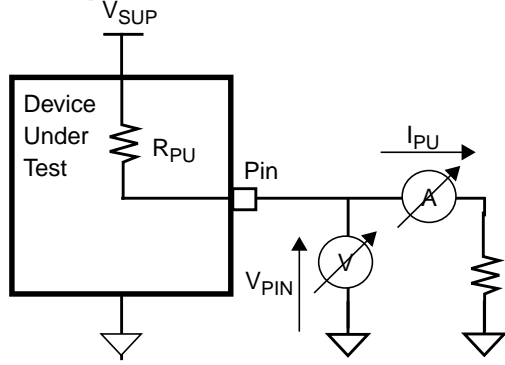
5-Volt Tolerance. An input signal that is 5V tolerant can operate with input voltage of up to 5V even though the supply to the device is only 3.3V. The actual maximum input voltage allowed to be supplied to the pin is indicated by the maximum high voltage allowed for the input buffer. Note that some pins have multiple buffers, not all of which are 5V tolerant. In such cases, there is a note that indicates at what conditions a 5V input may be applied to the pin; if there is no note, the low maximum voltage among the buffers is the maximum voltage allowed for the pin.

2.0 Device Characteristics (Continued)

2.3 INTERNAL RESISTORS

DC Test Conditions

Pull-Up Resistor Test Circuit



Pull-Down Resistor Test Circuit

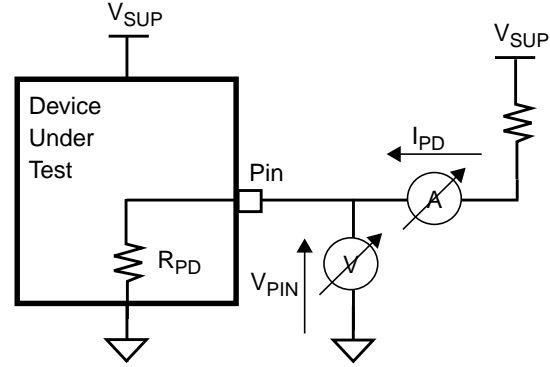


Figure 1. Internal Resistor Test Conditions, $T_A = 0\text{ }^{\circ}\text{C}$ to $70\text{ }^{\circ}\text{C}$, $V_{SUP} = 3.3\text{V}$

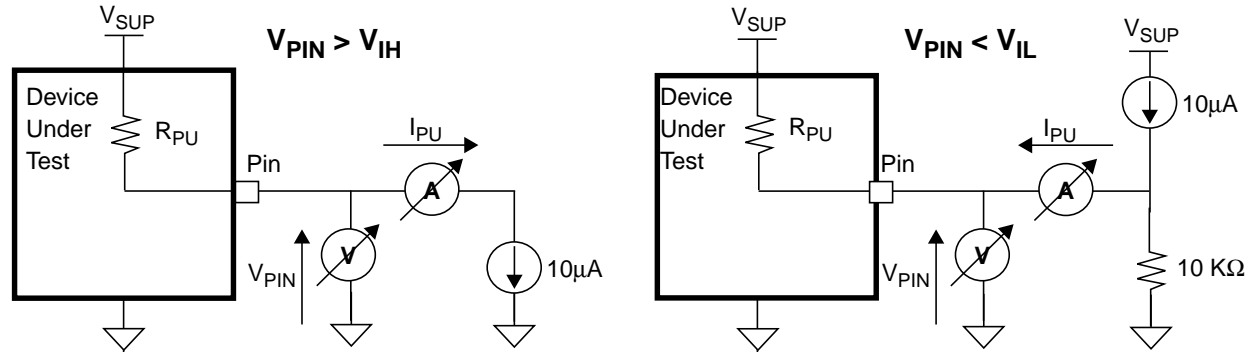


Figure 2. Internal Pull-Up Resistor for Straps, $T_A = 0\text{ }^{\circ}\text{C}$ to $70\text{ }^{\circ}\text{C}$, $V_{SUP} = 3.3\text{V}$

Notes for Figures 1 and 2:

- V_{SUP} is V_{DD} or V_{SB} according to the pin power well.
- The equivalent resistance of the pull-up resistor is calculated by $R_{PU} = (V_{SUP} - V_{PIN}) / I_{PU}$.
- The equivalent resistance of the pull-down resistor is calculated by $R_{PD} = V_{PIN} / I_{PD}$.

2.3.1 Pull-Up and Pull-Down Resistors

Symbol: PU_{nn} , PD_{nn}

Symbol	Parameter	Conditions ¹	Min ²	Typical	Max ²	Unit
R_{PU}	Pull-up equivalent resistance	$V_{PIN} = 0\text{V}$	$nn-30\%$	nn	$nn+30\%$	$\text{K}\Omega$
R_{PD}	Pull-down equivalent resistance	$V_{PIN} = V_{SUP}$	$nn-30\%$	nn	$nn+30\%$	$\text{K}\Omega$
		$V_{PIN} = 0.17 V_{SUP}^3$			$nn-50\%$	$\text{K}\Omega$
		$V_{PIN} = 0.8 V_{SUP}^3$	$nn-48\%$			$\text{K}\Omega$

1. $T_A = 0\text{ }^{\circ}\text{C}$ to $70\text{ }^{\circ}\text{C}$, $V_{SUP} = 3.3\text{V}$.

2. Not tested. Guaranteed by characterization.

3. For strap pins only.

2.0 Device Characteristics (Continued)

2.4 PACKAGE THERMAL INFORMATION

Thermal resistance (degrees C/W) Θ_{JA} and Θ_{JC} values for the PC87427 package are as follows:

Table 4. Θ_{JA} (°) J Values

Package Type	Θ_{JA} @0 lfpm	Θ_{JA} @225 lfpm	Θ_{JA} @500 lfpm	Θ_{JC}
128 PQFP	47	35.8	31.1	14.9

Note: Airflow for Θ_{JA} values is measured in linear feet per minute (lfpm).

2.5 AC ELECTRICAL CHARACTERISTICS

2.5.1 AC Test Conditions

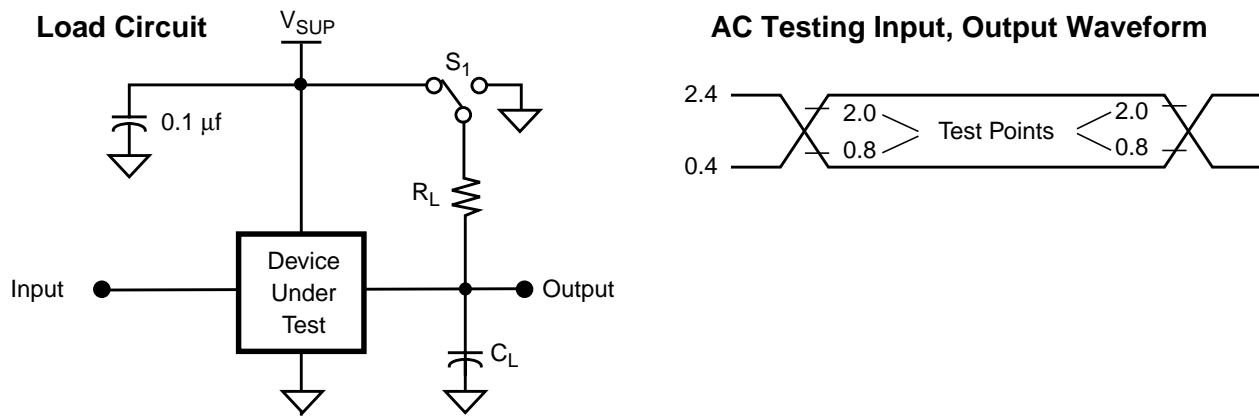


Figure 3. AC Test Conditions, $T_A = 0^\circ\text{C}$ to 70°C , $V_{SUP} = 3.3\text{V} \pm 10\%$

Notes:

- V_{SUP} is V_{DD} , V_{SB} or V_{PP} according to the pin power well.
- $C_L = 50$ pF for all output pins except the following pin groups:
 $C_L = 100$ pF for Serial Port 1, 2 and M (see Section 1.4.4 on page 10) and Floppy Disk Controller (see Section 1.4.9) pins;
 $C_L = 40$ pF for HFCKOUT pin;
 $C_L = 400$ pF for SMBus pins (see Section 1.4.2 on page 9);
 These values include both jig and oscilloscope capacitance.
- $S_1 = \text{Open}$ for push-pull output pins.
 $S_1 = V_{SUP}$ for high impedance to active low and active low to high impedance transition measurements.
 $S_1 = \text{GND}$ for high impedance to active high and active high to high impedance transition measurements.
 $R_L = 1.0$ K Ω for all the pins.
- For the FDC open-drain interface pins, $S_1 = V_{DD}$ and $R_L = 150$ Ω .

2.0 Device Characteristics (Continued)

2.5.2 Reset Timing

V_{SB} Power-Up Reset

Symbol	Figure	Description	Reference Conditions		Min ¹	Max ¹
t _{LRST}	5	Minimum $\overline{\text{LRESET}}$ active time	V _{SB} power-up to end of $\overline{\text{LRESET}}$		10 ms	
t _{IRST}	4	Internal Power-Up Reset Time	V _{SB} power-up to end of internal reset	Ended by 32 KHz Clock Domain	17 * t _{32KOSC}	t _{32KW} + t _{32KVAL} ² + 17 * t _{32KOSC}
	5			Ended by $\overline{\text{LRESET}}$	t _{LRST}	
t _{EPLV}	4, 5	External strap pull-down resistors, valid time	Before end of internal reset		t _{IRST}	
t _{IPLV}	4, 5	Internal strap pull-up resistors, valid time ³	Before end of internal reset		t _{IRST}	

1. Not tested. Guaranteed by design.

2. t_{32KW} + t_{32KVAL} from V_{BAT} power-up to 32 KHz domain toggling if V_{SB} and V_{BAT} are powered-up together; see “Low Frequency Clock Timing” on page 31.

3. Active only during V_{SB} Power-Up reset.

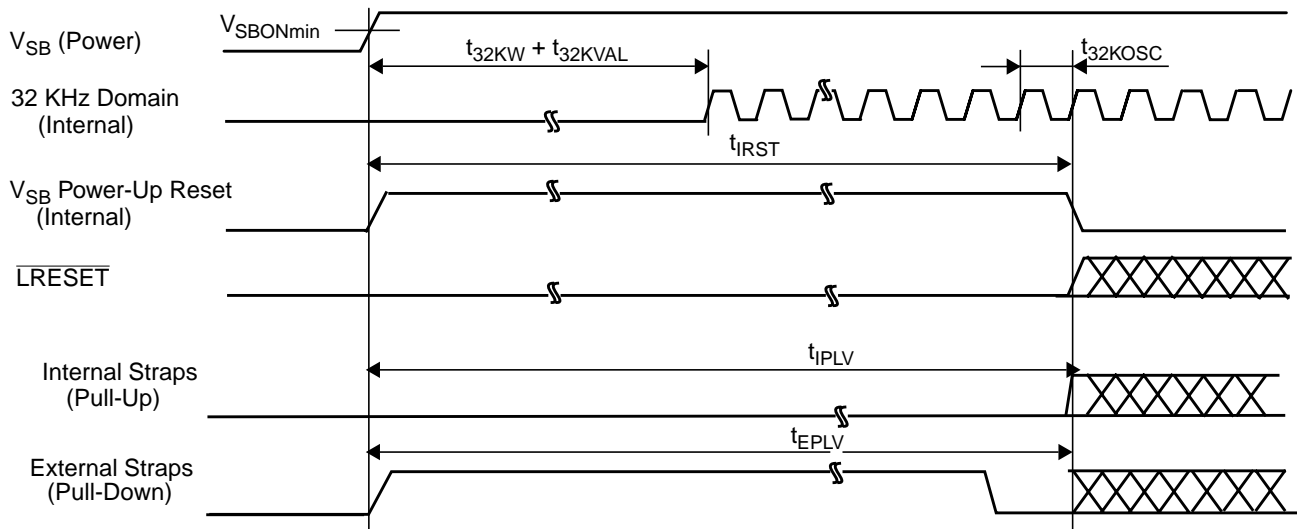


Figure 4. Internal V_{SB} Power-Up Reset - Ended by 32 KHz Clock Domain

2.0 Device Characteristics (Continued)

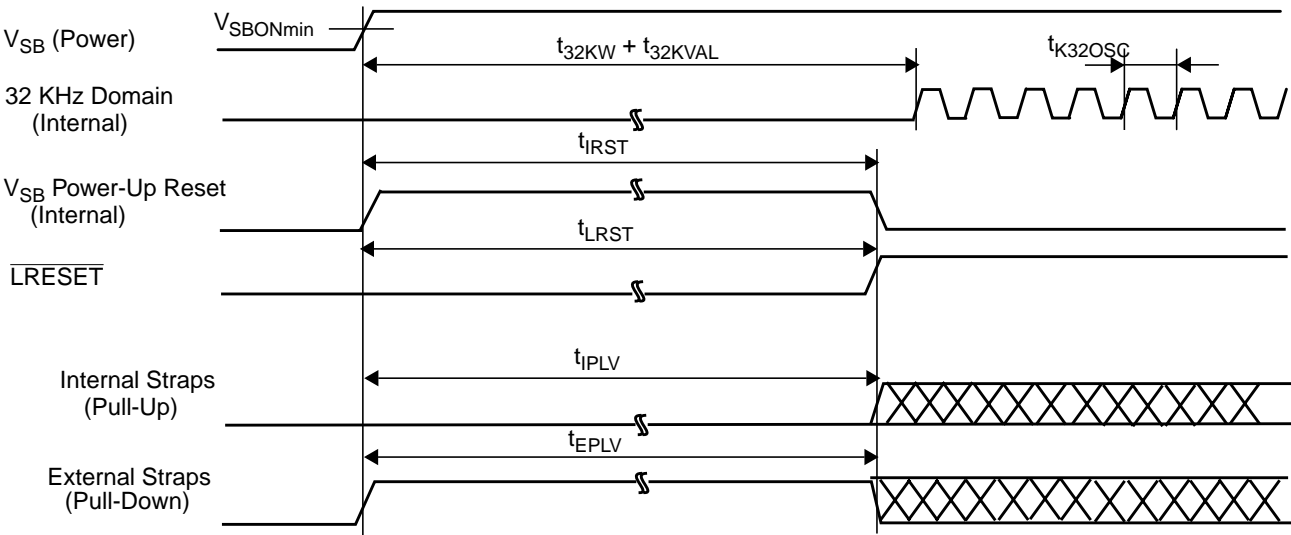


Figure 5. Internal V_{SB} Power-Up Reset - Ended by LRESET

V_{DD} Power-Up Reset

Symbol	Figure	Description	Reference Conditions	Min ¹	Max ¹
t _{LRST}	6	Minimum LRESET active time	V _{DD} power-up to end of LRESET	10ms	
t _{IRST}	6	Internal Power-Up reset time	V _{DD} power-up to end of internal reset	t _{LRST}	
t _{IPLV}	6	Internal strap pull-up resistors, valid time ²	Before end of internal reset	t _{IRST}	
t _{EPLV}	6	External strap pull-down resistors, valid time	Before end of internal reset	t _{IRST}	

1. Not tested. Guaranteed by design.
2. Active only during V_{DD} Power-Up reset.

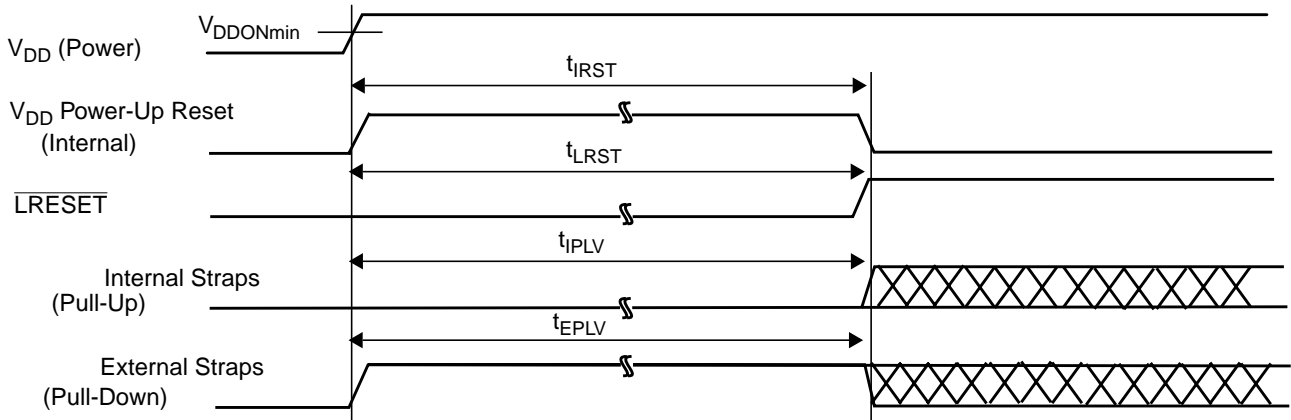


Figure 6. Internal V_{DD} Power-Up Reset

2.0 Device Characteristics (Continued)

Hardware Reset

Symbol	Figure	Description	Reference Conditions	Min	Max
t_{WRST}	7	\overline{LRESET} pulse width		100 ns	

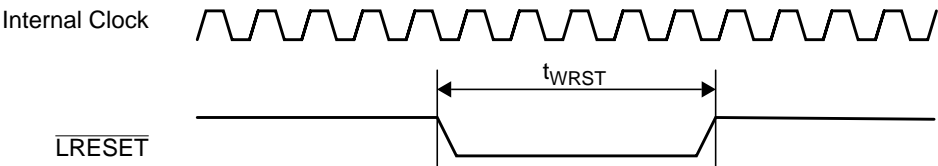


Figure 7. Hardware Reset

2.0 Device Characteristics (Continued)

2.5.3 Clock Timing

High Frequency Clock Timing

Symbol	Figure	Clock Input Parameters	Reference Conditions	CLKIN (48 MHz)			Units
				Min	Typ	Max	
t_{CH}	8	Clock High Pulse Width ¹		8			ns
t_{CL}	8	Clock Low Pulse Width ¹		8			ns
t_{CP}	8	Clock Period ¹ (50%-50%)		20.2	20.83	21.5	ns
F_{CK}	–	Clock Frequency		$F_{CKTYP} - 3\%$	⁴⁸ (F_{CKTYP})	$F_{CKTYP} + 3\%$	MHz
t_{CR}	8	Clock Rise Time ¹ (20%-80%)				2.2 ²	ns
t_{CF}	8	Clock Fall Time ¹ (80%-20%)				2.2 ²	ns
t_{CINW}	9	Clock Wake-Up Time	After $V_{SB} > V_{SBON}$			33	ms
t_{CINVAL}	9	Clock Valid Time ¹	Clock start toggling to clock within specification	System dependent			

1. Not tested. Guaranteed by design.

2. Recommended value

Symbol	Figure	Clock Output Parameter	HFCKOUT (48 MHz)			HFCKOUT (40 MHz)			Units
			Min	Typ	Max	Min	Typ	Max	
t_{CH}	8	Clock High Pulse Width ^{1,2}	8.2			10.3			ns
t_{CL}	8	Clock Low Pulse Width ^{1,2}	8.2			10.3			ns
t_{CP}	8	Clock Period ³ (50%-50%)	$t_{48TYP} - 32K_{TOL}^4 - 50ppm$	20.83 (t_{48TYP})	$t_{48TYP} + 32K_{TOL}^4 + 50ppm$	$t_{40TYP} - 32K_{TOL}^4 - 150ppm$	25 (t_{40TYP})	$t_{40TYP} + 32K_{TOL}^4 + 150ppm$	ns
t_{CR}	8	Clock Rise Time ² $C_L = 15$ pF (20%-80%)			2.5			2.5	ns
		$C_L = 40$ pF			5			5	ns
t_{CF}	8	Clock Fall Time ² $C_L = 15$ pF (80%-20%)			2.5			2.5	ns
		$C_L = 40$ pF			5			5	ns

1. $C_L = 15$ pF.

2. Not tested. Guaranteed by characterization.

3. Not tested. Guaranteed by design.

4. $32K_{TOL}$ = tolerance of $t_{32KCLKIN}$ parameter; see *Low Frequency Clock Timing*.

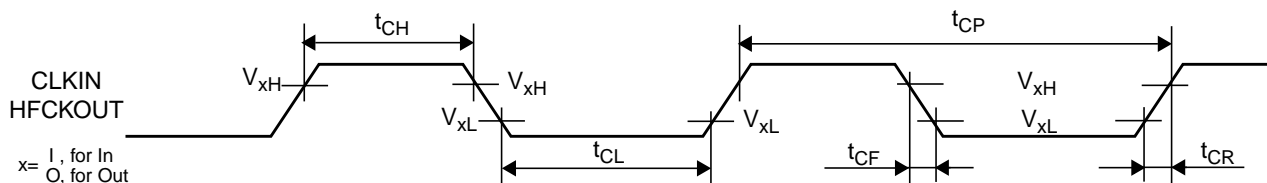


Figure 8. Clock Waveform Timing

2.0 Device Characteristics (Continued)

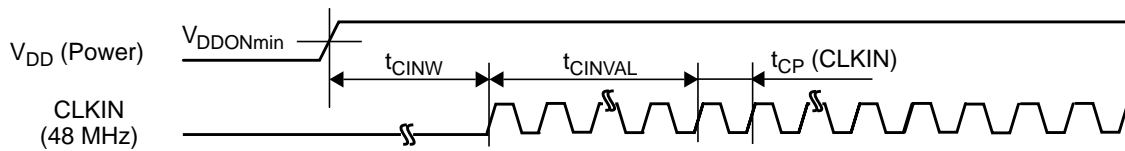


Figure 9. CLKIN Timing

Low Frequency Clock Timing

Symbol	Figure	Description	Reference Conditions	Min	Typ	Max	Units
Clock Input Timing							
$t_{32KCLKIN}$	–	Required clock period for 32KCLKIN ¹	From RE to RE of 32KCLKIN.	30.5145 ($t_{32TYP} - 100\text{ppm}$)	30.517578 (t_{32TYP})	30.5206 ($t_{32TYP} + 100\text{ppm}$)	μs
Clock Output Timing							
t_{32KOSC}	10	Clock period of the internal oscillator ²	From RE to RE of LFCKOUT.		30.517578 (t_{32TYP})		μs
$t_{32KW} + t_{32KVAL}$	10	32K oscillator wake-up time ³	After $V_{BAT} > V_{LOWBAT}$			1	sec
t_{32KD}	11	Internally generated 40/48 MHz clock delay time ³	After $V_{SB} > V_{SBON}$			33	ms

1. Recommended for RTC timekeeping accuracy and for HFCKOUT, LFCKOUT frequency accuracy.

2. Determined by the values of the external crystal circuit components.

3. Not tested. Guaranteed by characterization.

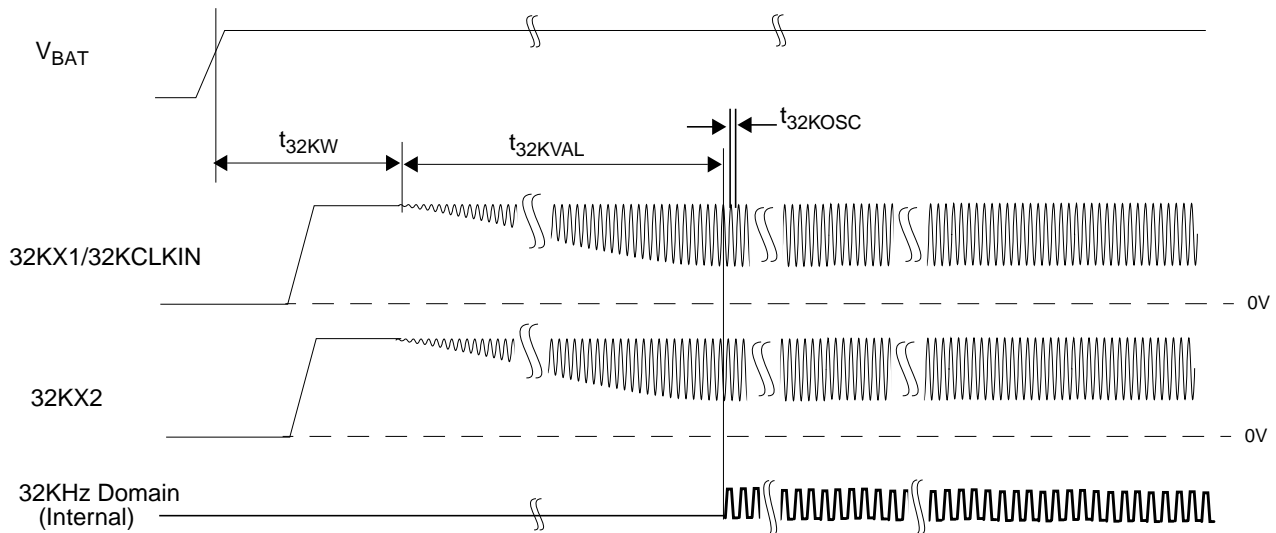


Figure 10. Low Frequency Clock Waveforms

2.0 Device Characteristics (Continued)

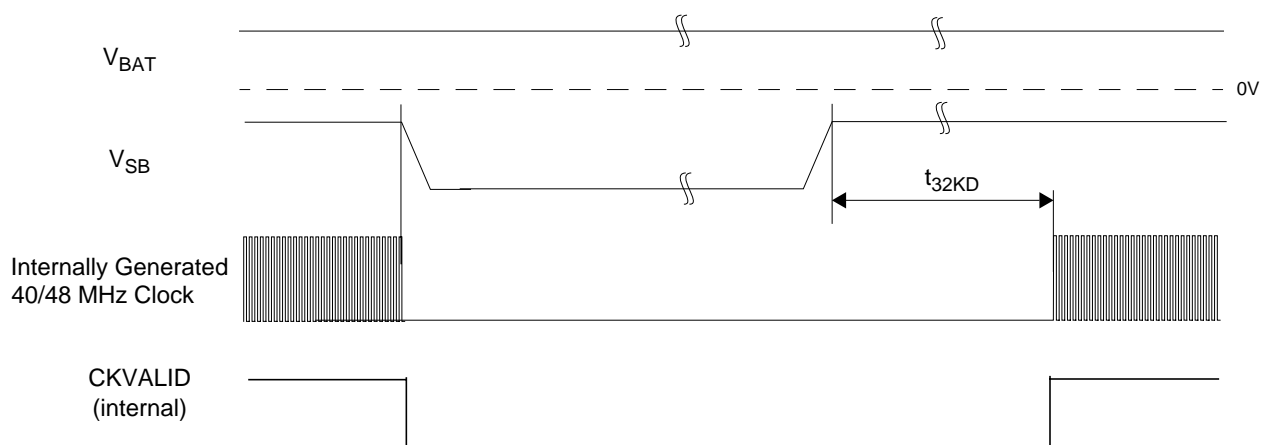


Figure 11. Internal Clock Waveforms

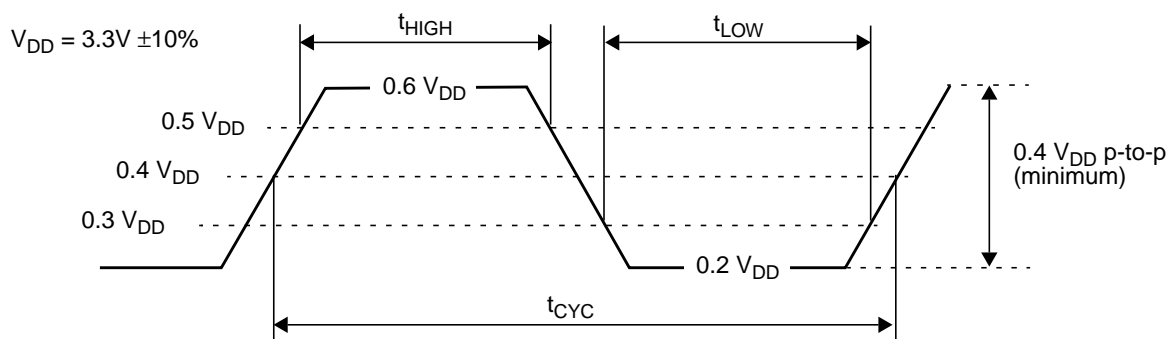
2.5.4 LPC Interface Timing

The AC characteristics of the LPC Interface meet the PCI Local Bus Specification (Rev 2.2 December 18, 1998) for 3.3V DC signaling.

LCLK and $\overline{\text{LRESET}}$

Symbol	Parameter	Min	Max	Units
t_{CYC}^1	LCLK Cycle Time	30		ns
t_{HIGH}^2	LCLK High Time ²	11		ns
t_{LOW}^2	LCLK Low Time ²	11		ns
-	LCLK Slew Rate ^{2,3}	1	4	V/ns
-	$\overline{\text{LRESET}}$ Slew Rate ^{2,4}	50		mV/ns

1. The PCI may have any clock frequency between nominal DC and 33 MHz. Device operational parameters at frequencies under 16 MHz are guaranteed by design rather than by testing. The clock frequency may be changed at any time during the operation of the system as long as the clock edges remain "clean" (monotonic) and the minimum cycle high and low times are not violated. The clock may only be stopped in a low state.
2. Not tested. Guaranteed by characterization.
3. Rise and fall times are specified in terms of the edge rate measured in V/ns. This slew rate must be met across the minimum peak-to-peak portion of the clock wavering ($0.2 V_{\text{DD}}$ to $0.6 V_{\text{DD}}$) as shown below.
4. The minimum $\overline{\text{LRESET}}$ slew rate applies only to the rising (de-assertion) edge of the reset signal and ensures that system noise cannot make an otherwise monotonic signal appear to bounce in the switching range.

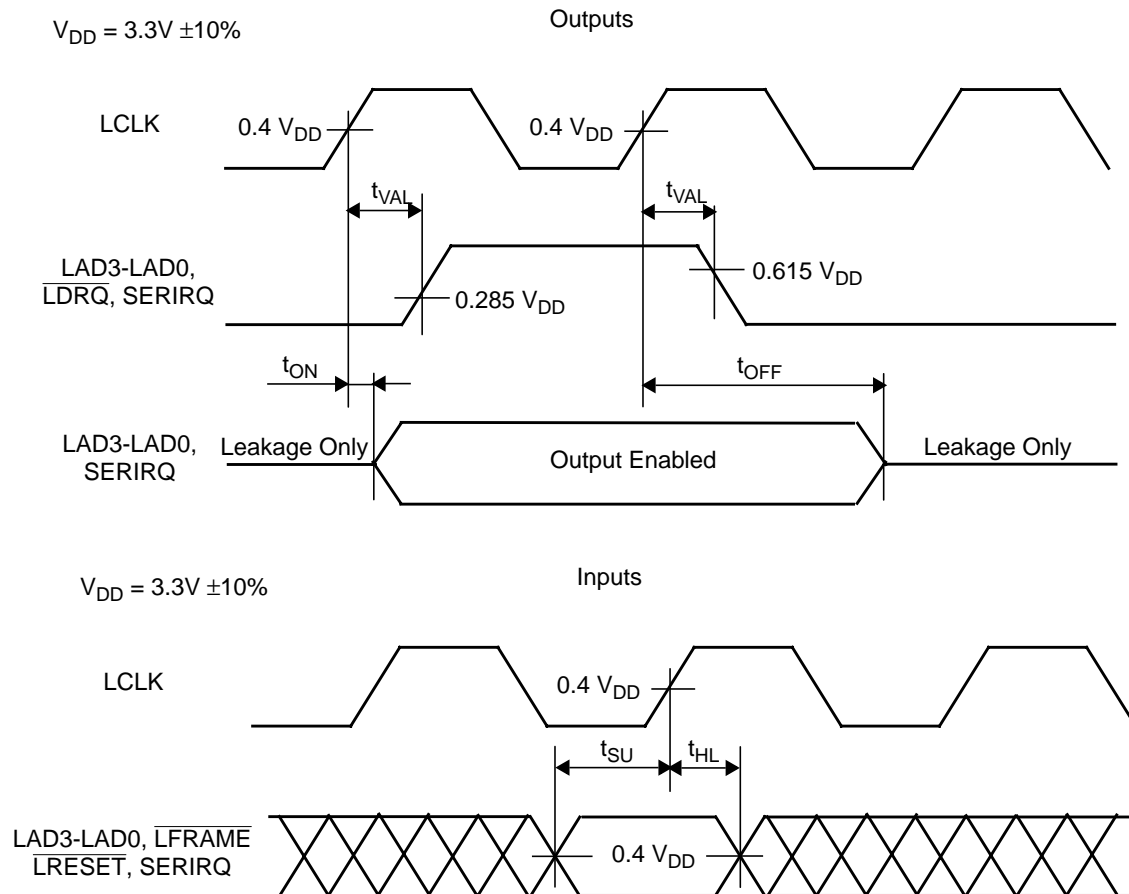


2.0 Device Characteristics (Continued)

SERIRQ and LPC Signals

Symbol	Figure	Description	Reference Conditions	Min	Max	Unit
t_{VAL}	Output	Output Valid Delay	After RE CLK	2	11	ns
t_{ON}	Output	Float to Active Delay	After RE CLK	2 ¹		ns
t_{OFF}	Output	Active to Float Delay	After RE CLK		28 ¹	ns
t_{SU}	Input	Input Setup Time	Before RE CLK	7		ns
t_{HL}	Input	Input Hold Time	After RE CLK	0		ns

1. Not tested. Guaranteed by characterization.



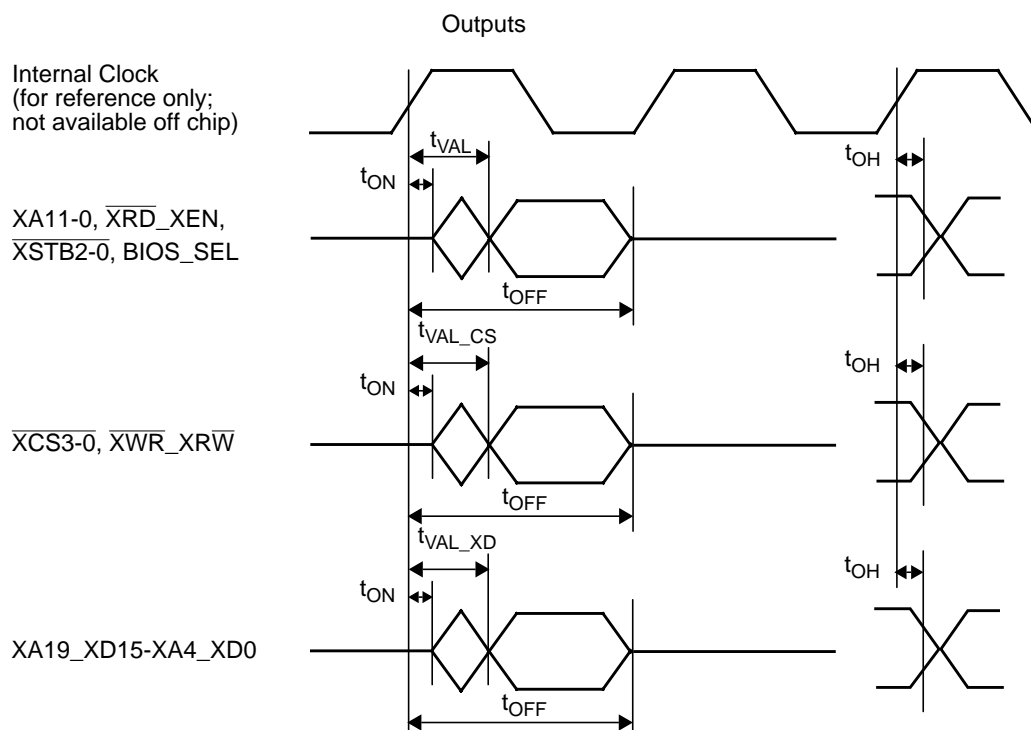
2.0 Device Characteristics (Continued)

2.5.5 X-Bus Extension Timing

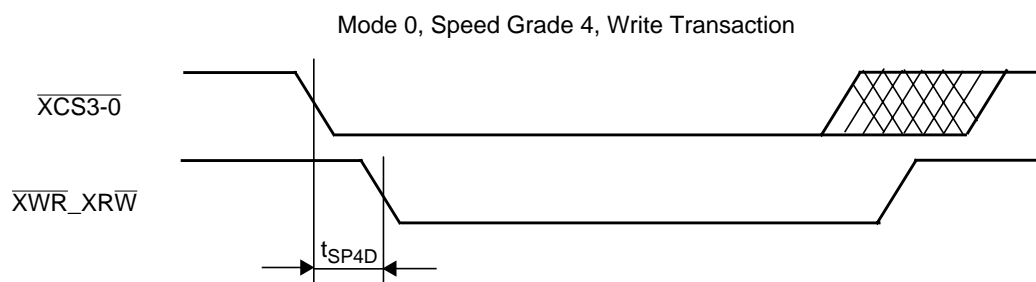
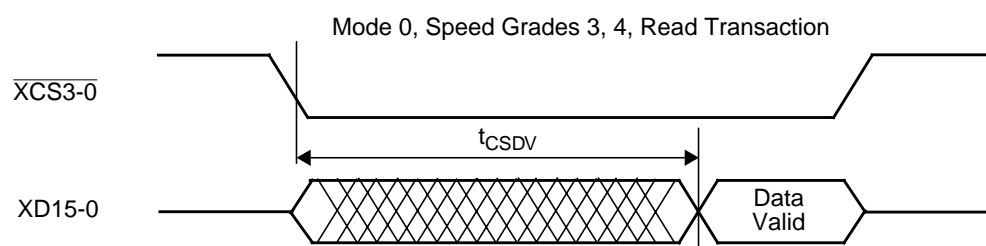
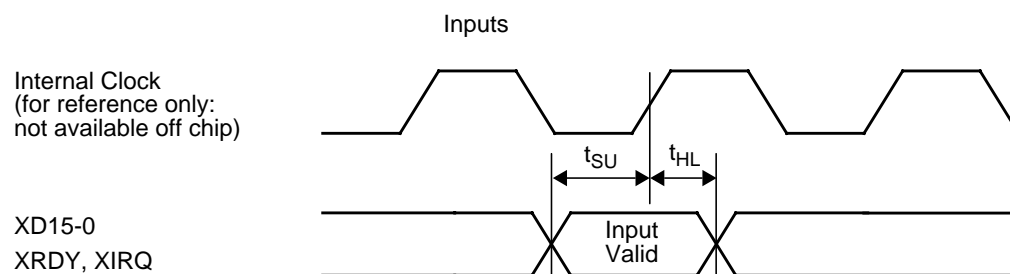
Symbol	Figure	Description	Reference Conditions		Min	Max	Unit
t_{VAL}	Outputs	Output Valid Delay	After RE Internal Clock	$C_L = 50 \text{ pF}$		22^1	ns
t_{VAL_CS}	Outputs	Output Valid Delay for XCS3-0, XWR_XRW	After RE Internal Clock	$C_L = 20 \text{ pF}$		12^1	ns
t_{VAL_XD}	Outputs	Output Valid Delay for XA19_XD15-XA4_XD0	After RE Internal Clock	$C_L = 20 \text{ pF}$		17^1	ns
				$C_L = 50 \text{ pF}$		20^1	ns
t_{ON}	Outputs	Float to Active Delay	After RE Internal Clock		0^2		ns
t_{OH}	Outputs	Output Hold time	After RE Internal Clock		0^2		ns
t_{OFF}	Outputs	Active to Float Delay	After RE Internal Clock	$C_L = 50 \text{ pF}$		30^1	ns
t_{CSDV}	Mode 0, Speed Grades 3, 4, Read Transaction	Chip Select active to Data Valid	Read from External Device	$C_L = 20 \text{ pF}$		73	ns
				$C_L = 50 \text{ pF}$		70	ns
t_{SP4D}	Mode 0, Speed Grade 4, Write Transaction	Chip Select active to XWR_XRW active delay	Write to External Device	$C_L = 20 \text{ pF}$	-0.5^1	0.5	ns

1. Not tested. Guaranteed by characterization.

2. Not tested. Guaranteed by design.



2.0 Device Characteristics (Continued)



2.0 Device Characteristics (Continued)

2.5.6 SMBus Timing

Symbol	Figure	Description	Type of Requirement ¹	Min	Max	Unit
t_{SMBR}	12	Rise time (SMBCLK and SMBDAT)	Input ²		1000 ³	ns
t_{SMBF}	12	Fall time (SMBCLK and SMBDAT)	Input		300 ³	ns
			Output ²		250 ⁴	ns
t_{SMBCKL}	12	Clock low period (SMBCLK)	Input	4.7		μs
t_{SMBCKH}	12	Clock high period (SMBCLK)	Input	4		μs
t_{SMBCY}	13	Clock cycle (SMBCLK)	Input	10		μs
t_{SMBDS}	13	Data setup time (before clock rising edge)	Input	250		ns
			Output ²	250		ns
t_{SMBDH}	13	Data hold time (after clock falling edge)	Input	0		ns
			Output ²	300		ns
t_{SMBPS}	14	Stop condition setup time (clock before data)	Input	4		μs
t_{SMBSH}	14	Start condition hold time (clock after data)	Input	4		μs
t_{SMBBUF}	14	Bus free time between Stop and Start conditions (SMBDAT)	Input	4.7		μs
t_{SMBRS}	15	Restart condition setup time (clock before data)	Input	4.7		μs
t_{SMBRH}	15	Restart condition hold time (clock after data)	Input	4		μs
t_{SMBLEX}	-	Cumulative clock low extend time from Start to Stop (SMBCLK)	Output		25 ³	ms
t_{SMBTO}	-	Clock low time-out (SMBCLK)	Input	25 ^{3,5}		ms
			Output		35 ^{3,6}	ms

1. An "Input" type is a value the PC87427 expects from the system; an "Output" type is a value the PC87427 provides to the system.

2. Test conditions: $R_L = 1 \text{ K}\Omega$ to $V_{\text{SB}} = 3.3\text{V}$, $C_L = 400 \text{ pF}$ to GND.

3. Not tested. Guaranteed by design.

4. Not tested. Guaranteed by characterization.

5. The PC87427 detects a time-out condition if SMBCLK is held low for more than t_{SMBTO} .

6. Upon detection of a time-out condition, the PC87427 resets the SMBus Interface no later than t_{SMBTO} .

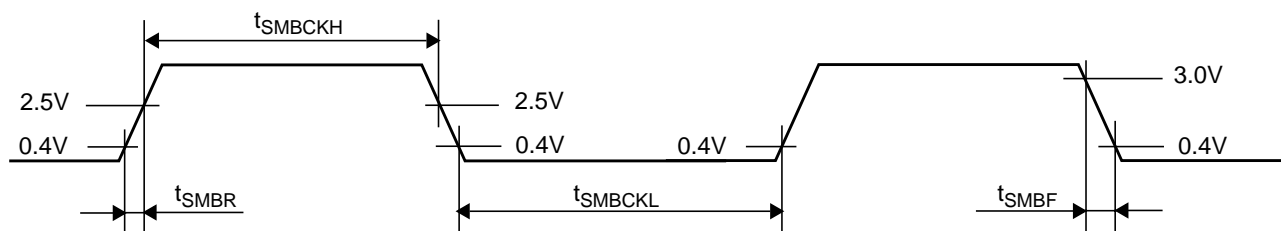


Figure 12. SMBus Signals (SMBCLK and SMBDAT) Rising Time and Falling Time

2.0 Device Characteristics (Continued)

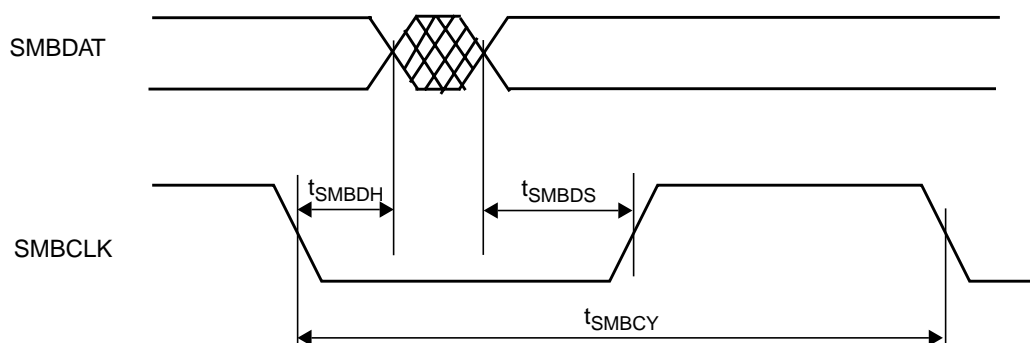


Figure 13. SMBus Data Bit Timing

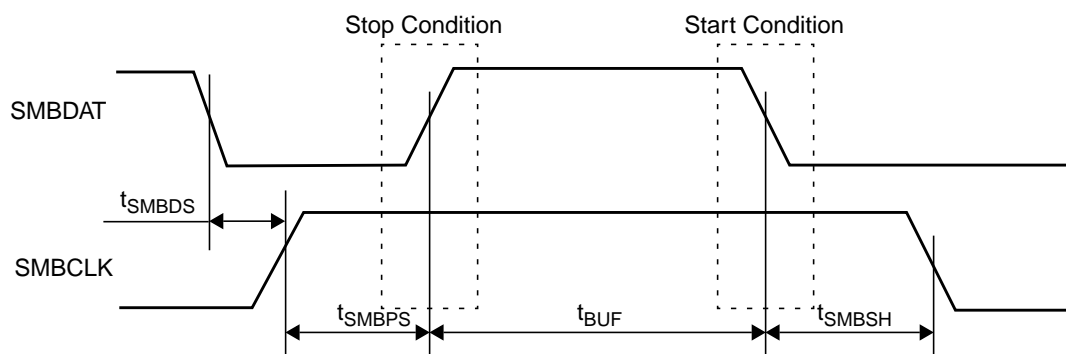


Figure 14. SMBus Start and Stop Condition Timing

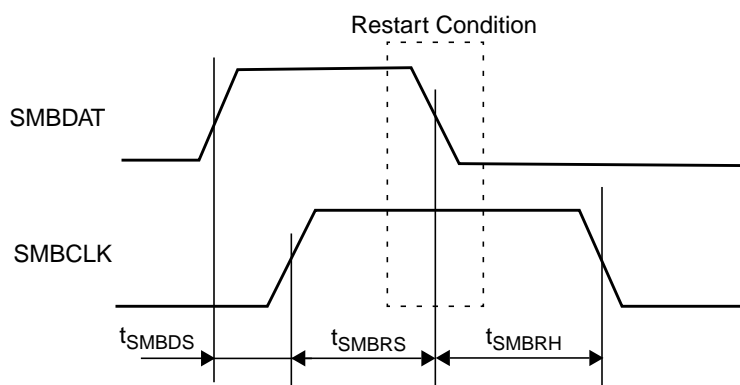


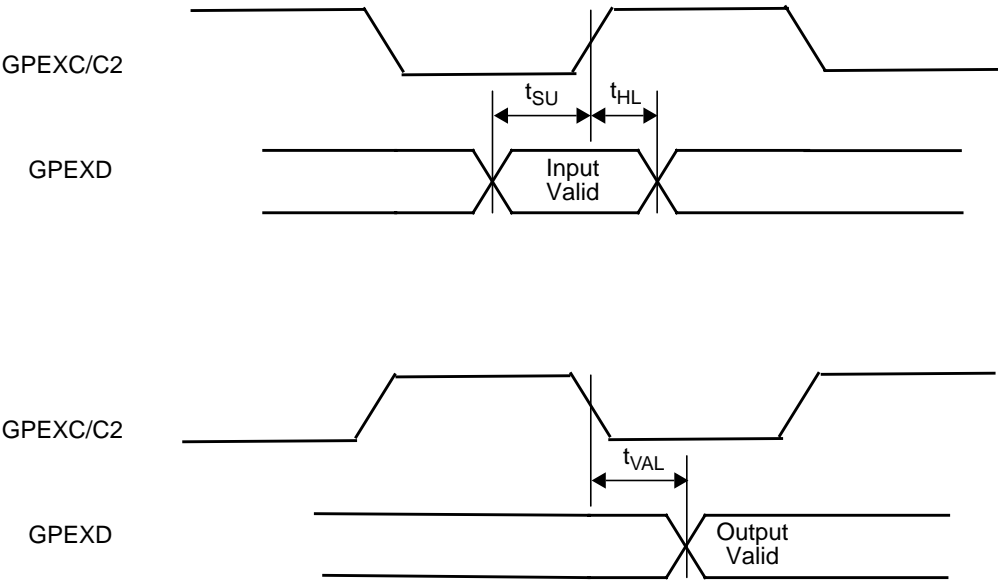
Figure 15. SMBus Restart Condition Timing

2.0 Device Characteristics (Continued)

2.5.7 GPE Timing

Symbol	Figure	Description	Reference Conditions		Min	Max	Unit
t _{VAL}	Outputs	Output Valid Delay	After clock falling edge	C _L = 20 pF		4 ¹	ns
t _{SU}	Inputs	Input Setup Time	Before clock rising edge		12 ¹		ns
t _{HL}	Inputs	Input Hold Time	After clock rising edge		0 ¹		ns

1. Not tested. Guaranteed by characterization.



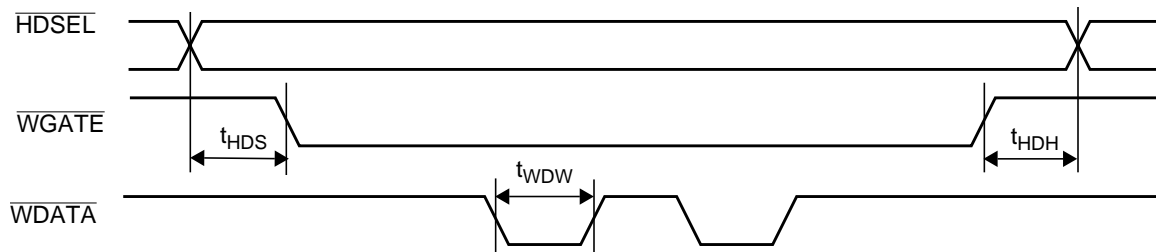
2.0 Device Characteristics (Continued)

2.5.8 FDC Timing

FDC Write Data Timing

Symbol	Parameter	Min	Max	Unit
t_{HDH}	\overline{HDSEL} Hold from \overline{WGATE} Inactive ¹	100		μs
t_{HDS}	\overline{HDSEL} Setup to \overline{WGATE} Active ¹	100		μs
t_{WDW}	Write Data Pulse Width ¹	See t_{DRP} , t_{ICP} and t_{WDW} values in table below		

1. Not tested. Guaranteed by design.



t_{DRP} t_{ICP} t_{WDW} Values

Data Rate	t_{DRP}	t_{ICP}	t_{ICP} Nominal	t_{WDW}	t_{WDW} Minimum	Unit
1 Mbps	1000	$6 \times t_{CP}^1$	125	$2 \times t_{ICP}$	250	ns
500 Kbps	2000	$6 \times t_{CP}^1$	125	$2 \times t_{ICP}$	250	ns
300 Kbps	3333	$10 \times t_{CP}^1$	208	$2 \times t_{ICP}$	375	ns
250 Kbps	4000	$12 \times t_{CP}^1$	250	$2 \times t_{ICP}$	500	ns

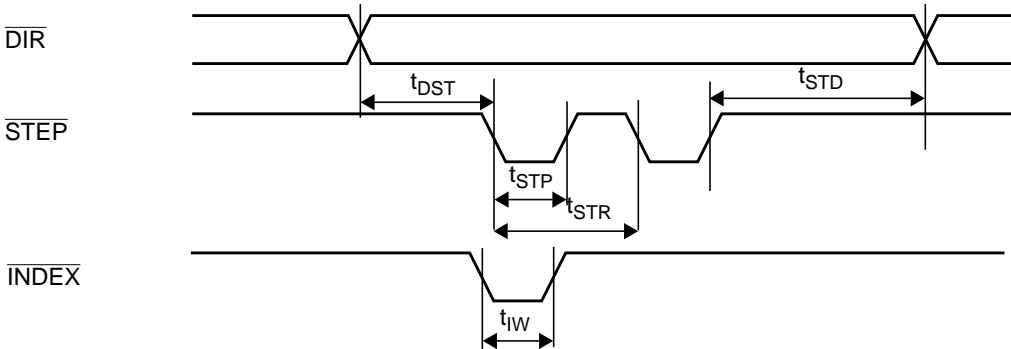
1. t_{CP} is the clock period defined for CLKIN in *Clock Timing* on page 30.

FDC Drive Control Timing

Symbol	Parameter	Min	Max	Unit
t_{DST}	\overline{DIR} Setup to \overline{STEP} Active ¹	6		μs
t_{IW}	Index Pulse Width	100		ns
t_{STD}	\overline{DIR} Hold from \overline{STEP} Inactive	t_{STR}		ms
t_{STP}	\overline{STEP} Active High Pulse Width ¹	8		μs
t_{STR}	\overline{STEP} Rate Time ¹	0.5		ms

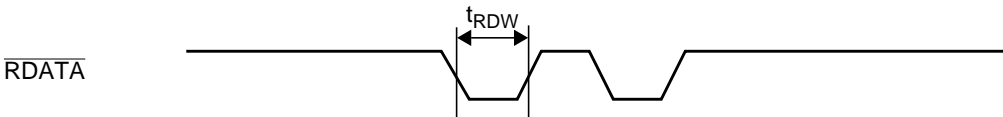
1. Not tested. Guaranteed by design.

2.0 Device Characteristics (Continued)



FDC Read Data Timing

Symbol	Parameter	Min	Max	Unit
t_{RDW}	Read Data Pulse Width	50		ns

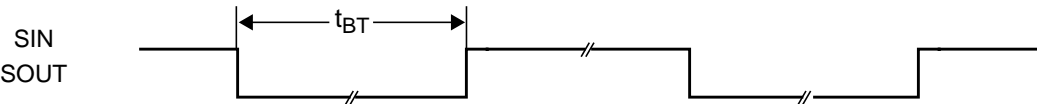


2.5.9 Serial Interfaces 1, 2 and M Timing

Serial Port Data Timing

Symbol	Parameter	Conditions	Min	Max	Unit
t_{BT}	Single Bit Time in Serial Interface ¹	Transmitter	$t_{\text{BTN}} - 25^2$	$t_{\text{BTN}} + 25^2$	ns
		Receiver	$t_{\text{BTN}} - 2\%^2$	$t_{\text{BTN}} + 2\%^2$	ns

1. Not tested. Guaranteed by design.
2. t_{BTN} is the nominal bit time in the Serial Interface; it is determined by the setting of the Baud Generator Divisor registers.



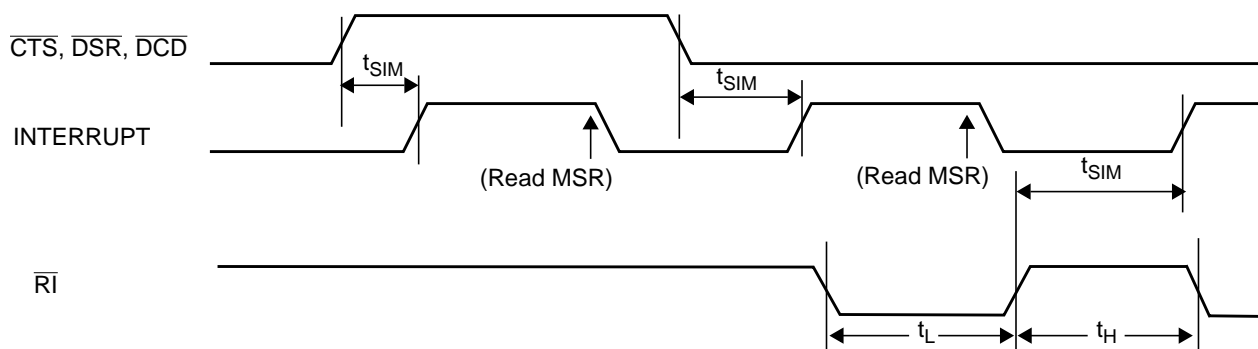
2.0 Device Characteristics (Continued)

Modem Control Timing

Symbol	Parameter	Min	Max	Unit
t_L	\overline{RI} Low Time ^{1,2}	10		ns
t_H	\overline{RI} High Time ^{1,2}	10		ns
t_{SIM}	Delay to Set IRQ from Modem Input		40	ns

1. Not tested. Guaranteed by characterization

2. This value also applies to $\overline{RI2}$,1 wake-up detection in the SWC module.



2.5.10 SWC Timing

Wake-Up Inputs at V_{SB} Power Switching

Symbol	Figure	Description	Reference Conditions	Min	Max
t_{EWIV}	16	External Wake-up inputs not valid ¹	At V_{SB} power on, after the 32 KHz Domain is toggling	$24576 \cdot t_{32KOSC}$ ²	$32768 \cdot t_{32KOSC}$
t_{PBOP}	17	$\overline{PWBTOUT}$ pulse time ¹	Resume by $\overline{SLPS3}$, $\overline{SLPS5}$ after Power Fail	100 ms ³	100.03 ms

1. Not tested. Guaranteed by design.

2. t_{32KOSC} is the cycle time of the 32 KHz clock domain (see "Low Frequency Clock Timing" on page 31)

3. Except when generated by \overline{PWBTIN} pulse.

2.0 Device Characteristics (Continued)

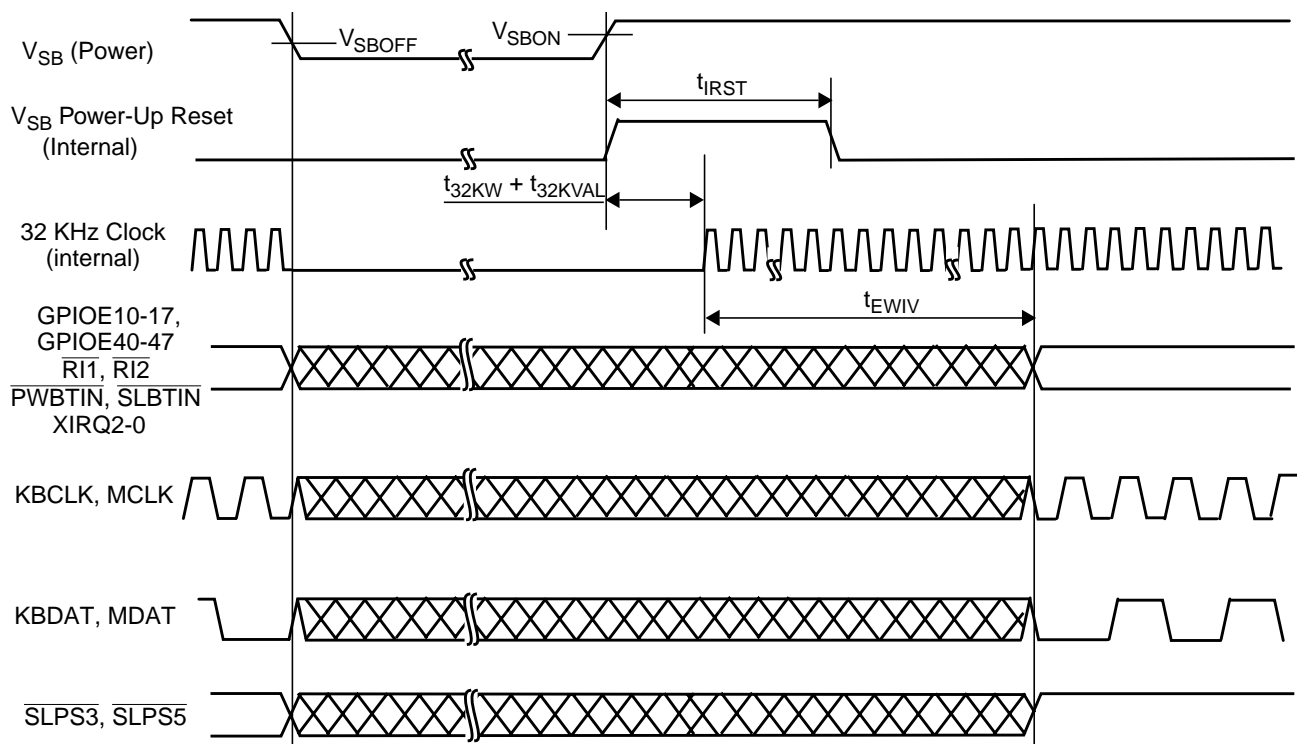


Figure 16. Inputs at V_{SB} Power Switching (No V_{BAT})

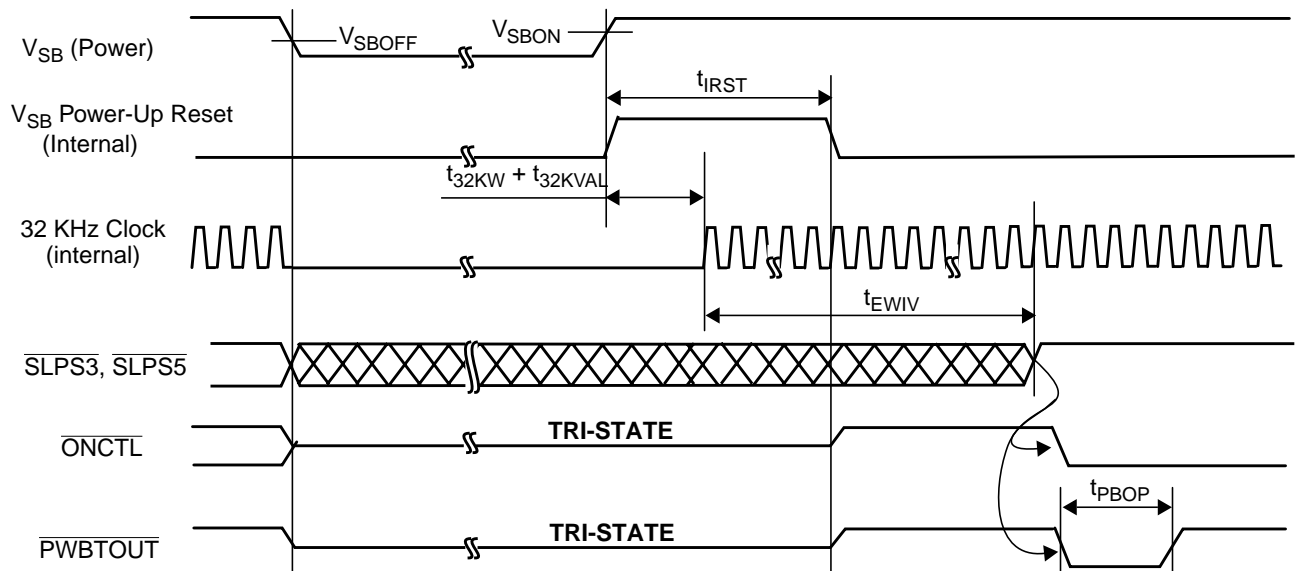


Figure 17. Resume by $\overline{SLPS3}$, $\overline{SLPS5}$, After Power Fail (No V_{BAT})

2.0 Device Characteristics (Continued)

Wake-Up Inputs at V_{DD} Power Switching

Symbol	Figure	Description	Reference Conditions	Min	Max
t_{EWIV}	18	External Wake-up inputs valid ¹	After V_{DD} power On ²	$24576 \cdot t_{32KOSC}^3$	$32768 \cdot t_{32KOSC}$

1. Not tested. Guaranteed by design.

2. The 32 KHz clock domain is assumed to be toggling at V_{DD} power stable.

3. t_{32KOSC} is the cycle time of the 32 KHz clock domain (see "Low Frequency Clock Timing" on page 31)

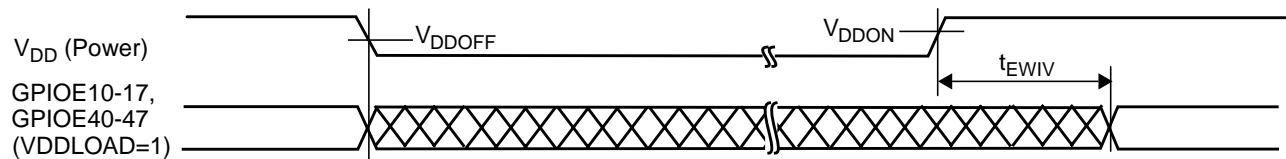


Figure 18. Wake-Up Inputs at V_{DD} Power Switching

Power Button Override

Symbol	Figure	Description	Reference Conditions	Min	Max
t_{PBOV}	19	Power Button Override ¹	After \overline{PWBTIN} active	3.89 s	3.92 s
t_{OVEX}	19	Power Button Override Extension ¹	After the end of t_{PBOV}	0.2 s	0.24 s
t_{PBID}	19	\overline{PWBTIN} disable time ¹	After a Power-Off event	1 s	1.25 s

1. Not tested. Guaranteed by design.

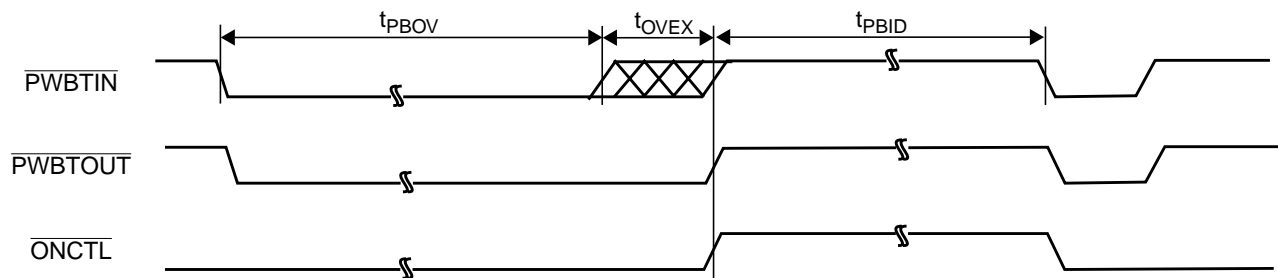


Figure 19. Power Button Override Timing

2.0 Device Characteristics (Continued)

Crowbar

Symbol	Figure	Description	Reference Conditions	Min	Max
t_{CBTO}	20, 21	Crowbar Timeout ¹	After \overline{ONCTL} active, or V_{DD} power fall	0.5 s^2	20 s^2
t_{CBPBO}	20, 21	Crowbar generated, $\overline{PWBTOUT}$ pulse time ¹	After completion of Crowbar Timeout	4 s	4.25 s
t_{PBID}	20, 21	\overline{PWBTIN} disable time ¹	After a Power-Off event	1 s	1.25 s

1. Not tested. Guaranteed by design.

2. Set by $CRBAR_TOUT$.

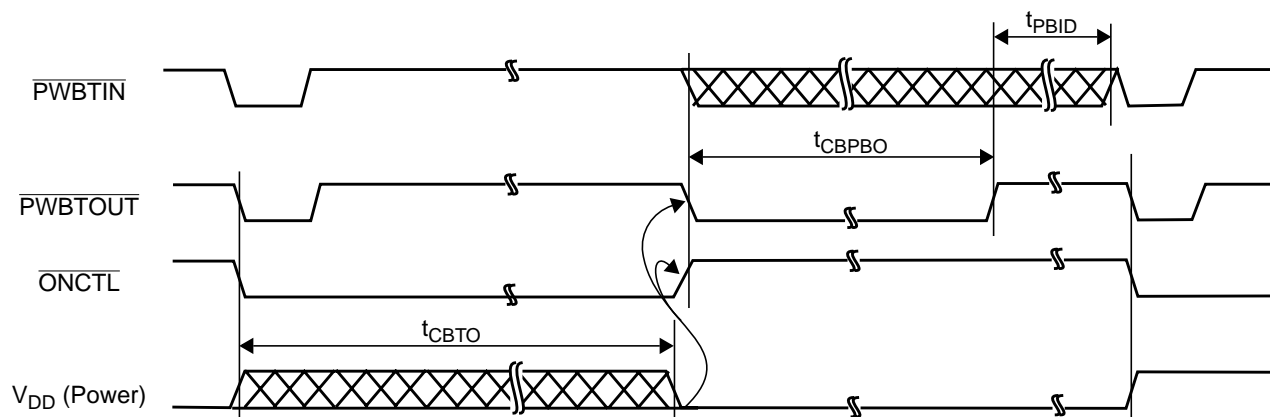


Figure 20. Power-On Crowbar Timing

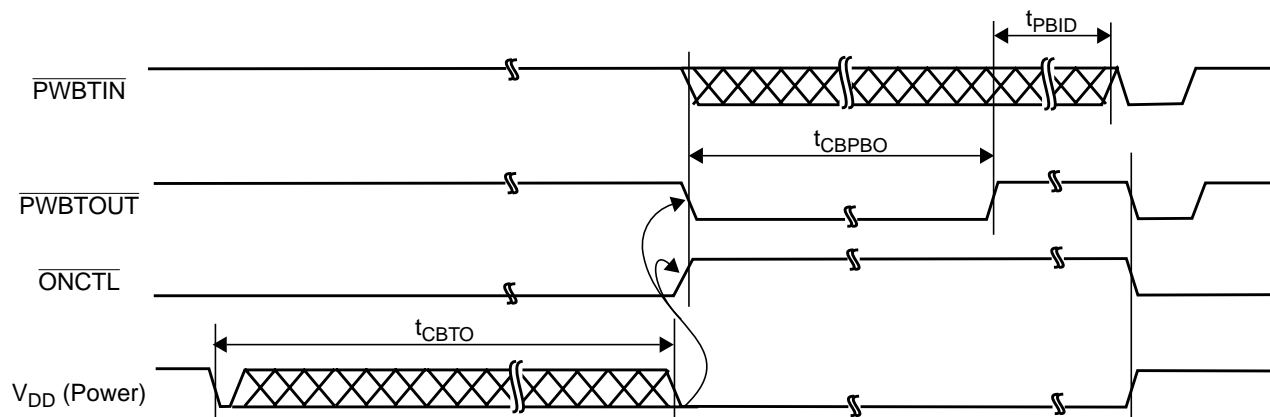


Figure 21. Power-Fall Crowbar Timing

2.0 Device Characteristics (Continued)

System Watchdog Power-Off / ETC

Symbol	Figure	Description	Reference Conditions	Min	Max
t_{PBO}	22	$\overline{PWBTOUT}$ pulse time ¹		4 s	4.25 s
t_{PBID}	22	\overline{PWBTIN} disable time ¹	After a Power-Off event	1 s	1.25 s

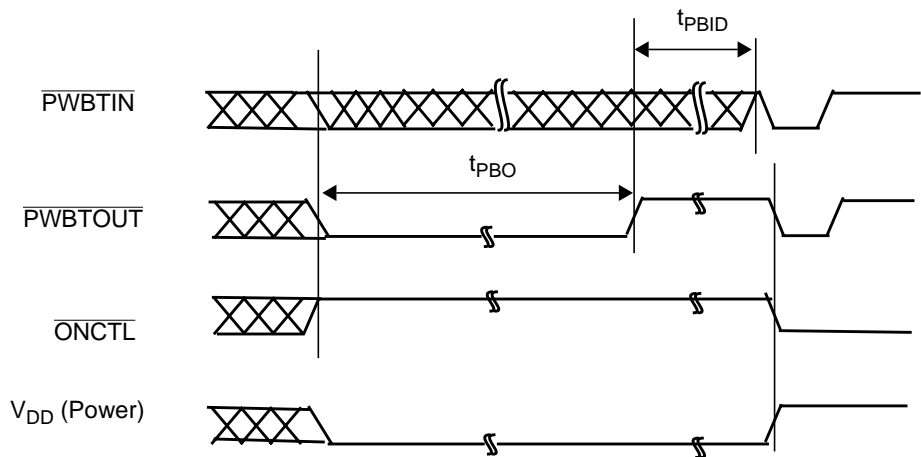
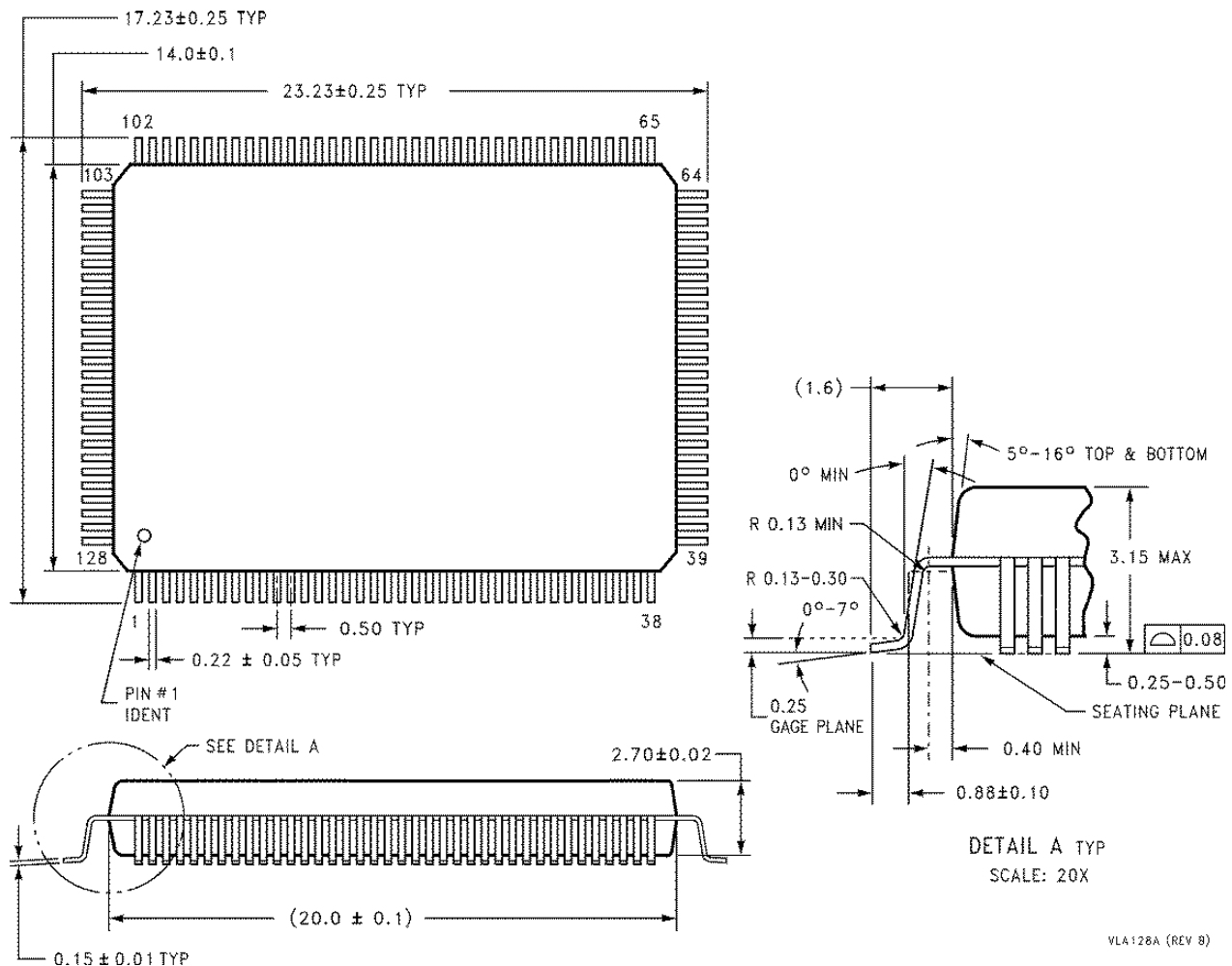


Figure 22. Watchdog Power-Off / ETC Timing

Physical Dimensions

All dimensions are in millimeters



VLA128A (REV 8)

Plastic Quad Flatpack (PQFP), JEDEC
Order Number PC87427-xxx/VLA
NS Package Number VLA128A

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